

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E6 instruction tests for VRI-i encoded:
				5 *
				6 * E658 VCVD - VECTOR CONVERT TO DECIMAL (32)
				7 * E65A VCVDG - VECTOR CONVERT TO DECIMAL (64)
				8 *
				9 * James Wekel June 2024
				10 *****
				11
				12 *****
				13 *
				14 * basic instruction tests
				15 *
				16 *****
				17 * This program tests proper functioning of the z/arch E6 VRI-i vector
				18 * convert to decimal. Exceptions are not tested.
				19 *
				20 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 * obvious coding errors. None of the tests are thorough. They are
				22 * NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 * *Testcase zvector-e6-13-converttodecimal: VECTOR E6 VRI-i instruction
				27 * *
				28 * * Zvector E6 tests for VRI-i encoded instruction:
				29 * *
				30 * * E658 VCVD - VECTOR CONVERT TO DECIMAL (32)
				31 * * E65A VCVDG - VECTOR CONVERT TO DECIMAL (64)
				32 * *
				33 * * # -----
				34 * * # This tests only the basic function of the instruction.
				35 * * # Exceptions are NOT tested.
				36 * * # -----
				37 * *
				38 * main size 2
				39 * numcpu 1
				40 * sysclear
				41 * archlvl z/Arch
				42 *
				43 * diag8cmd enable # (needed for messages to Hercules console)
				44 * loadcore "\$(testpath)/zvector-e6-13-converttodecimal.core" 0x0
				45 * diag8cmd disable # (reset back to default)
				46 *
				47 * *Done
				48 *
				49 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				51 *****
				52 * FCHECK Macro - Is a Facility Bit set?
				53 *
				54 * If the facility bit is NOT set, an message is issued and
				55 * the test is skipped.
				56 *
				57 * Fcheck uses R0, R1 and R2
				58 *
				59 * eg. FCHECK 134, 'vector-packed-decimal'
				60 *****
				61 MACRO
				62 FCHECK &BITNO, &NOTSETMSG
				63 . * &BITNO : facility bit number to check
				64 . * &NOTSETMSG : 'facility name'
				65 LCLA &FBBYTE Facility bit in Byte
				66 LCLA &FBBIT Facility bit within Byte
				67
				68 LCLA &L(8)
				69 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				70
				71 &FBBYTE SETA &BITNO/8
				72 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				73 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				74
				75 B X&SYSNDX
				76 * Fcheck data area
				77 * skip messgae
				78 SKT&SYSNDX DC C' Skipping tests: '
				79 DC C&NOTSETMSG
				80 DC C' facility (bit &BITNO) is not installed.'
				81 SKL&SYSNDX EQU *-SKT&SYSNDX
				82 * facility bits
				83 DS FD gap
				84 FB&SYSNDX DS 4FD
				85 DS FD gap
				86 *
				87 X&SYSNDX EQU *
				88 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				89 STFLE FB&SYSNDX get facility bits
				90
				91 XGR R0, R0
				92 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				93 N R0, =F' &FBBIT' is bit set?
				94 BNZ XC&SYSNDX
				95 *
				96 * facility bit not set, issue message and exit
				97 *
				98 LA R0, SKL&SYSNDX message length
				99 LA R1, SKT&SYSNDX message address
				100 BAL R2, MSG
				101
				102 B EOJ
				103 XC&SYSNDX EQU *
				104 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				126 *****
				127 * The actual "ZVE6TST" program itself...
				128 *****
				129 *
				130 * Architecture Mode: z/Arch
				131 * Register Usage:
				132 *
				133 * R0 (work)
				134 * R1-4 (work)
				135 * R5 Testing control table - current test base
				136 * R6- R7 (work)
				137 * R8 First base register
				138 * R9 Second base register
				139 * R10 Third base register
				140 * R11 E6TEST call return
				141 * R12 E6TESTS register
				142 * R13 (work)
				143 * R14 Subroutine call
				144 * R15 Secondary Subroutine call or work
				145 *
				146 *****
00000200		00000200		148 USING BEGIN, R8 FIRST Base Register
00000200		00001200		149 USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		150 USING BEGIN+8192, R10 THIRD Base Register
				151
00000200	0580			152 BEGIN BALR R8, 0 Initalize FIRST base register
00000202	0680			153 BCTR R8, 0 Initalize FIRST base register
00000204	0680			154 BCTR R8, 0 Initalize FIRST base register
				155
00000206	4190 8800		00000800	156 LA R9, 2048(, R8) Initalize SECOND base register
0000020A	4190 9800		00000800	157 LA R9, 2048(, R9) Initalize SECOND base register
				158
0000020E	41A0 9800		00000800	159 LA R10, 2048(, R9) Initalize THIRD base register
00000212	41A0 A800		00000800	160 LA R10, 2048(, R10) Initalize THIRD base register
				161
00000216	B600 834C		0000054C	162 STCTL R0, R0, CTLR0 Store CRO to enable AFP
0000021A	9604 834D		0000054D	163 OI CTLR0+1, X' 04' Turn on AFP bit
0000021E	9602 834D		0000054D	164 OI CTLR0+1, X' 02' Turn on Vector bit
00000222	B700 834C		0000054C	165 LCTL R0, R0, CTLR0 Reload updated CRO
				166
				167 *****
				168 * Is Vector packed-decimal facility installed (bit 134)
				169 *****
				170
00000226	47F0 80B0		000002B0	171 FCHECK 134, ' vector-packed- decimal '
				172+ B X0001
				173+ * Fcheck data area
				174+ * skip messgae
0000022A	40404040 40404040			175+SKT0001 DC C' Skipping tests: '
00000244	A58583A3 96996097			176+ DC C' vector-packed-decimal '
00000259	40868183 899389A3			177+ DC C' facility (bit 134) is not installed. '
		00000054 00000001		178+SKL0001 EQU *- SKT0001
				179+ * facility bits
00000280	00000000 00000000			180+ DS FD gap
00000288	00000000 00000000			181+FB0001 DS 4FD

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						233	*****
						234	* cc was not as expected
						235	*****
0000031A	E310	0001	0082	0000031A	00000001	236	CCMSG EQU *
00000320	E310	5008	0076		00000001	237	XG R1, R1
00000326	5410	835C			00000008	238	LB R1, M4 m3 has CS bit
0000032A	4780	80FE			0000055C	239	N R1, =F' 1' get CS (CC set) bit
					000002FE	240	BZ TESTREST ignore if not set
						241	*
						242	* extract CC extracted PSW
						243	*
0000032E	5810	8EE8			000010E8	244	L R1, CCPSW
00000332	8810	000C			0000000C	245	SRL R1, 12
00000336	5410	8360			00000560	246	N R1, =XL4' 3'
0000033A	4210	8EF0			000010F0	247	STC R1, CCFOUND save cc
						248	*
						249	* FILL IN MESSAGE
						250	*
0000033E	4820	5004			00000004	251	LH R2, TNUM get test number and convert
00000342	4E20	8ED5			000010D5	252	CVD R2, DECNUM
00000346	D211	8EBF	8EA9	000010BF	000010A9	253	MVC PRT3, EDIT
0000034C	DE11	8EBF	8ED5	000010BF	000010D5	254	ED PRT3, DECNUM
00000352	D202	8E64	8ECC	00001064	000010CC	255	MVC CCPRTNUM(3), PRT3+13 fill in message with test #
						256	
00000358	D207	8E81	500B	00001081	0000000B	257	MVC CCPRTNAME, OPNAME fill in message with instruction
						258	
0000035E	B982	0022				259	XGR R2, R2 get CC as U8
00000362	4320	5009			00000009	260	IC R2, CC
00000366	4E20	8ED5			000010D5	261	CVD R2, DECNUM and convert
0000036A	D211	8EBF	8EA9	000010BF	000010A9	262	MVC PRT3, EDIT
00000370	DE11	8EBF	8ED5	000010BF	000010D5	263	ED PRT3, DECNUM
00000376	D200	8E97	8ECE	00001097	000010CE	264	MVC CCPRTEXP(1), PRT3+15 fill in message with CC field
						265	
0000037C	B982	0022				266	XGR R2, R2 get CCFOUND as U8
00000380	4320	8EF0			000010F0	267	IC R2, CCFOUND
00000384	4E20	8ED5			000010D5	268	CVD R2, DECNUM and convert
00000388	D211	8EBF	8EA9	000010BF	000010A9	269	MVC PRT3, EDIT
0000038E	DE11	8EBF	8ED5	000010BF	000010D5	270	ED PRT3, DECNUM
00000394	D200	8EA7	8ECE	000010A7	000010CE	271	MVC CCPRTGOT(1), PRT3+15 fill in message with ccfound
						272	
0000039A	4100	0055			00000055	273	LA R0, CCPRTLNG message length
0000039E	4110	8E54			00001054	274	LA R1, CCPRTLNE messagfe address
000003A2	45F0	8230			00000430	275	BAL R15, RPTERROR
						276	
000003A6	47F0	8212			00000412	277	B FAILCONT

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						279 *****	
						280 * result not as expected:	
						281 * issue message with test number, instruction under test	
						282 * and instruction l2	
						283 *****	
				000003AA	00000001	284 FAILMSG EQU *	
000003AA	4820	5004			00000004	285 LH R2, TNUM	get test number and convert
000003AE	4E20	8ED5			000010D5	286 CVD R2, DECNUM	
000003B2	D211	8EBF 8EA9		000010BF	000010A9	287 MWC PRT3, EDIT	
000003B8	DE11	8EBF 8ED5		000010BF	000010D5	288 ED PRT3, DECNUM	
000003BE	D202	8E18 8ECC		00001018	000010CC	289 MWC PRTNUM(3), PRT3+13	fill in message with test #
						290	
000003C4	D207	8E33 500B		00001033	0000000B	291 MWC PRTNAME, OPNAME	fill in message with instruction
						292	
000003CA	B982	0022				293 XGR R2, R2	get i3 as U8
000003CE	4320	5007			00000007	294 IC R2, I3	and convert
000003D2	4E20	8ED5			000010D5	295 CVD R2, DECNUM	
000003D6	D211	8EBF 8EA9		000010BF	000010A9	296 MWC PRT3, EDIT	
000003DC	DE11	8EBF 8ED5		000010BF	000010D5	297 ED PRT3, DECNUM	
000003E2	D202	8E44 8ECC		00001044	000010CC	298 MWC PRTI3(3), PRT3+13	fill in message with i3 field
						299	
000003E8	B982	0022				300 XGR R2, R2	get m4 as U8
000003EC	4320	5008			00000008	301 IC R2, M4	and convert
000003F0	4E20	8ED5			000010D5	302 CVD R2, DECNUM	
000003F4	D211	8EBF 8EA9		000010BF	000010A9	303 MWC PRT3, EDIT	
000003FA	DE11	8EBF 8ED5		000010BF	000010D5	304 ED PRT3, DECNUM	
00000400	D202	8E51 8ECD		00001051	000010CD	305 MWC PRTM4(3), PRT3+14	fill in message with m4 field
						306	
00000406	4100	004C			0000004C	307 LA R0, PRTLNG	message length
0000040A	4110	8E08			00001008	308 LA R1, PRTLNE	messagfe address
0000040E	45F0	8230			00000430	309 BAL R15, RPTERROR	
						311 *****	
						312 * continue after a failed test	
						313 *****	
				00000412	00000001	314 FAILCONT EQU *	
00000412	5800	835C			0000055C	315 L R0, =F' 1'	set GLOBAL failed test indicator
00000416	5000	8E00			00001000	316 ST R0, FAILED	
						317	
0000041A	41C0	C004			00000004	318 LA R12, 4(0, R12)	next test address
0000041E	47F0	80DC			000002DC	319 B NEXTE6	
						321 *****	
						322 * end of testing; set ending psw	
						323 *****	
				00000422	00000001	324 ENDTEST EQU *	
00000422	5810	8E00			00001000	325 L R1, FAILED	did a test fail?
00000426	1211					326 LTR R1, R1	
00000428	4780	8330			00000530	327 BZ EOJ	No, exit
0000042C	47F0	8348			00000548	328 B FAILTEST	Yes, exit with BAD PSW
						329	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				394 *****
				395 * Normal completion or Abnormal termination PSWs
				396 *****
00000520	00020001 80000000			398 E0JPSW DC OD' 0' , X' 0002000180000000' , AD(0)
00000530	B2B2 8320		00000520	400 E0J LPSWE E0JPSW Normal completion
00000538	00020001 80000000			402 FAILPSW DC OD' 0' , X' 0002000180000000' , AD(X' BAD')
00000548	B2B2 8338		00000538	404 FAILTEST LPSWE FAILPSW Abnormal termination
				406 *****
				407 * Working Storage
				408 *****
0000054C	00000000			410 CTLR0 DS F CRO
00000550	00000000			411 DS F
00000554				413 LTORG , Literals pool
00000554	00000002			414 =F' 2'
00000558	00003560			415 =A(E6TESTS)
0000055C	00000001			416 =F' 1'
00000560	00000003			417 =XL4' 3'
00000564	0000			418 =H' 0'
00000566	005F			419 =AL2(L' MSGMSG)
				420
				421 * some constants
				422
	00000400	00000001		423 K EQU 1024 One KB
	00001000	00000001		424 PAGE EQU (4*K) Size of one page
	00010000	00000001		425 K64 EQU (64*K) 64 KB
	00100000	00000001		426 MB EQU (K*K) 1 MB
				427
				428
	AABBCCDD	00000001		429 REG2PATT EQU X' AABBCCDD' Polluted Register pattern
	000000DD	00000001		430 REG2LOW EQU X' DD' (last byte above)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				432 *=====
				433 *
				434 * NOTE: start data on an address that is easy to display
				435 * within Hercules
				436 *
				437 *=====
				438
00000568		00000568	00001000	439 ORG ZVE6TST+X' 1000'
00001000	00000000			440 FAILED DC F' 0' some test failed?
00001004	00000000			441 TESTING DC F' 0' current test number
				443 *****
				444 * TEST failed : result messgae
				445 *****
				446 *
				447 * failed message and associated editting
				448 *
00001008	40404040	40404040		449 PRTLNE DC C' Test # '
00001018	A7A7A7			450 PRTNUM DC C' xxx'
0000101B	40868189	93858440		451 DC C' failed for instruction '
00001033	A7A7A7A7	A7A7A7A7		452 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3	884089F3		453 DC C' with i3=
00001044	A7A7A76B			454 PRTI3 DC C' xxx, '
00001048	40A689A3	884094F4		455 DC C' with m4=
00001051	A7A7			456 PRTM4 DC C' xx'
00001053	4B			457 DC C' .'
		0000004C	00000001	458 PRTLNG EQU *- PRTLNE
				460 *****
				461 * TEST failed : CC message
				462 *****
				463 *
				464 * failed message and associated editting
				465 *
00001054	40404040	40404040		466 CCPRTLNE DC C' Test # '
00001064	A7A7A7			467 CCPRTNUM DC C' xxx'
00001067	40A69996	95874083		468 DC c' wrong cc for instruction '
00001081	A7A7A7A7	A7A7A7A7		469 CCPRTNAME DC CL8' xxxxxxxx'
00001089	4085A797	8583A385		470 DC C' expected: cc=
00001097	A7			471 CCPRTEXP DC C' x'
00001098	6B			472 DC C' ,'
00001099	40998583	8589A585		473 DC C' received: cc=
000010A7	A7			474 CCPRTGOT DC C' x'
000010A8	4B			475 DC C' .'
		00000055	00000001	476 CCPRTLNG EQU *- CCPRTLNE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				534 *****
				535 * Macros to help build test tables
				536 *-----
				537 * VRR_K Macro to help build test tables
				538 *****
				539 MACRO
				540 VRR_K &INST, &I3, &M4, &CC
				541 . * &INST - instruction under test
				542 . * &I3
				543 . * &M4
				544 . * &CC - expected CC
				545 . *
				546 LCLA &XCC(4) &CC has mask values for FAILED condition codes
				547 &XCC(1) SETA 7 CC != 0
				548 &XCC(2) SETA 11 CC != 1
				549 &XCC(3) SETA 13 CC != 2
				550 &XCC(4) SETA 14 CC != 3
				551
				552 GBLA &TNUM
				553 &TNUM SETA &TNUM+1
				554
				555 DS OFD
				556 USING *, R5 base for test data and test routine
				557
				558 T&TNUM DC A(X&TNUM) address of test routine
				559 DC H' &TNUM test number
				560 DC XL1' 00'
				561 DC HL1' &I3' i3
				562 DC HL1' &M4' m4
				563 DC HL1' &CC' cc
				564 DC HL1' &XCC(&CC+1)' cc failed mask
				565
				566 DC CL8' &INST' instruction name
				567
				568 DC A(16) result length
				569 REA&TNUM DC A(RE&TNUM) result address
				570 . *
				571 * INSTRUCTION UNDER TEST ROUTINE
				572 X&TNUM DS OF
				573 VL V1, V1FUDGE pollute V1
				574 LG R2, RE&TNUM+16 get R2 source
				575
				576 &INST V1, R2, &I3, &M4 test instruction
				577
				578 VST V1, V10OUTPUT save
				579 EPSW R2, R0 exptract psw
				580 ST R2, CCPSW to save CC
				581
				582 BR R11 return
				583
				584 RE&TNUM DC OF
				585 DROP R5
				586
				587 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001290	00000000 0000001D					
00001298	FFFFFFFF FFFFFFFF			721	DC FD' - 1'	R2 source
				722		
				723	VRR_K VCVD, 159, 1, 0	INT_MAX
000012A0				724+	DS OFD	
000012A0		000012A0		725+	USING *, R5	base for test data and test routine
000012A0	000012BC			726+T4	DC A(X4)	address of test routine
000012A4	0004			727+	DC H' 4'	test number
000012A6	00			728+	DC XL1' 00'	
000012A7	9F			729+	DC HL1' 159'	i3
000012A8	01			730+	DC HL1' 1'	m4
000012A9	00			731+	DC HL1' 0'	cc
000012AA	07			732+	DC HL1' 7'	cc failed mask
000012AB	E5C3E5C4 40404040			733+	DC CL8' VCVD'	instruction name
000012B4	00000010			734+	DC A(16)	result length
000012B8	000012E0			735+REA4	DC A(RE4)	result address
				736+*		INSTRUCTION UNDER TEST ROUTINE
000012BC				737+X4	DS OF	
000012BC	E710 8F48 0006		00001148	738+	VL V1, V1FUDGE	pollute V1
000012C2	E320 5050 0004		000012F0	739+	LG R2, RE4+16	get R2 source
000012C8	E612 0019 F058			740+	VCVD V1, R2, 159, 1	test instruction
000012CE	E710 8F10 000E		00001110	741+	VST V1, V10UTPUT	save
000012D4	B98D 0020			742+	EPSW R2, R0	exptract psw
000012D8	5020 8EE8		000010E8	743+	ST R2, CCPSW	to save CC
000012DC	07FB			744+	BR R11	return
000012E0				745+RE4	DC OF	
000012E0				746+	DROP R5	
000012E0	00000000 00000000			747	DC XL16' 000000000000000000000002147483647C'	V1 result
000012E8	00000214 7483647C					
000012F0	00000000 7FFFFFFF			748	DC FD' 2147483647'	R2 source
				749		
				750	VRR_K VCVD, 159, 1, 0	INT_MIN
000012F8				751+	DS OFD	
000012F8		000012F8		752+	USING *, R5	base for test data and test routine
000012F8	00001314			753+T5	DC A(X5)	address of test routine
000012FC	0005			754+	DC H' 5'	test number
000012FE	00			755+	DC XL1' 00'	
000012FF	9F			756+	DC HL1' 159'	i3
00001300	01			757+	DC HL1' 1'	m4
00001301	00			758+	DC HL1' 0'	cc
00001302	07			759+	DC HL1' 7'	cc failed mask
00001303	E5C3E5C4 40404040			760+	DC CL8' VCVD'	instruction name
0000130C	00000010			761+	DC A(16)	result length
00001310	00001338			762+REA5	DC A(RE5)	result address
				763+*		INSTRUCTION UNDER TEST ROUTINE
00001314				764+X5	DS OF	
00001314	E710 8F48 0006		00001148	765+	VL V1, V1FUDGE	pollute V1
0000131A	E320 5050 0004		00001348	766+	LG R2, RE5+16	get R2 source
00001320	E612 0019 F058			767+	VCVD V1, R2, 159, 1	test instruction
00001326	E710 8F10 000E		00001110	768+	VST V1, V10UTPUT	save
0000132C	B98D 0020			769+	EPSW R2, R0	exptract psw
00001330	5020 8EE8		000010E8	770+	ST R2, CCPSW	to save CC
00001334	07FB			771+	BR R11	return
00001338				772+RE5	DC OF	
00001338				773+	DROP R5	
00001338	00000000 00000000			774	DC XL16' 000000000000000000000002147483648D'	V1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001340	00000214 7483648D					
00001348	FFFFFFFF 80000000			775	DC	FD' - 2147483648' R2 source
				776		
				777 *	VCVD	m4= 1 (LB=0, P1=0 , CS=1)
				778 *		i3= 137 (IOM=1, RDC= 9)
				779		
				780	VRR_K	VCVD, 137, 1, 0
00001350				781+	DS	OFD
00001350		00001350		782+	USING	*, R5 base for test data and test routine
00001350	0000136C			783+T6	DC	A(X6) address of test routine
00001354	0006			784+	DC	H' 6' test number
00001356	00			785+	DC	XL1' 00'
00001357	89			786+	DC	HL1' 137' i3
00001358	01			787+	DC	HL1' 1' m4
00001359	00			788+	DC	HL1' 0' cc
0000135A	07			789+	DC	HL1' 7' cc failed mask
0000135B	E5C3E5C4 40404040			790+	DC	CL8' VCVD' instruction name
00001364	00000010			791+	DC	A(16) result length
00001368	00001390			792+REA6	DC	A(RE6) result address
				793+*		INSTRUCTION UNDER TEST ROUTINE
0000136C				794+X6	DS	OF
0000136C	E710 8F48 0006		00001148	795+	VL	V1, V1FUDGE pollute V1
00001372	E320 5050 0004		000013A0	796+	LG	R2, RE6+16 get R2 source
00001378	E612 0018 9058			797+	VCVD	V1, R2, 137, 1 test instruction
0000137E	E710 8F10 000E		00001110	798+	VST	V1, V10UTPUT save
00001384	B98D 0020			799+	EPSW	R2, R0 exptract psw
00001388	5020 8EE8		000010E8	800+	ST	R2, CCPSW to save CC
0000138C	07FB			801+	BR	R11 return
00001390				802+RE6	DC	OF
00001390				803+	DROP	R5
00001390	00000000 00000000			804	DC	XL16' 00000000000000000000000000000000C' V1 result
00001398	00000000 0000000C					
000013A0	00000000 00000000			805	DC	FD' 0' R2 source
				806		
				807	VRR_K	VCVD, 137, 1, 0
000013A8				808+	DS	OFD
000013A8		000013A8		809+	USING	*, R5 base for test data and test routine
000013A8	000013C4			810+T7	DC	A(X7) address of test routine
000013AC	0007			811+	DC	H' 7' test number
000013AE	00			812+	DC	XL1' 00'
000013AF	89			813+	DC	HL1' 137' i3
000013B0	01			814+	DC	HL1' 1' m4
000013B1	00			815+	DC	HL1' 0' cc
000013B2	07			816+	DC	HL1' 7' cc failed mask
000013B3	E5C3E5C4 40404040			817+	DC	CL8' VCVD' instruction name
000013BC	00000010			818+	DC	A(16) result length
000013C0	000013E8			819+REA7	DC	A(RE7) result address
				820+*		INSTRUCTION UNDER TEST ROUTINE
000013C4				821+X7	DS	OF
000013C4	E710 8F48 0006		00001148	822+	VL	V1, V1FUDGE pollute V1
000013CA	E320 5050 0004		000013F8	823+	LG	R2, RE7+16 get R2 source
000013D0	E612 0018 9058			824+	VCVD	V1, R2, 137, 1 test instruction
000013D6	E710 8F10 000E		00001110	825+	VST	V1, V10UTPUT save
000013DC	B98D 0020			826+	EPSW	R2, R0 exptract psw
000013E0	5020 8EE8		000010E8	827+	ST	R2, CCPSW to save CC
000013E4	07FB			828+	BR	R11 return

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT		
00001498					883+RE9	DC	OF
00001498					884+	DROP	R5
00001498	00000000	00000000			885	DC	XL16' 000000000000000000000000147483647C' V1 result t
000014A0	00000014	7483647C					
000014A8	00000000	7FFFFFFF			886	DC	FD' 2147483647' R2 source
					887		
					888	VRR_K	VCVD, 137, 1, 3 INT_MIN
000014B0					889+	DS	OFD
000014B0			000014B0		890+	USING	*, R5 base for test data and test routine
000014B0	000014CC				891+T10	DC	A(X10) address of test routine
000014B4	000A				892+	DC	H' 10' test number
000014B6	00				893+	DC	XL1' 00'
000014B7	89				894+	DC	HL1' 137' i3
000014B8	01				895+	DC	HL1' 1' m4
000014B9	03				896+	DC	HL1' 3' cc
000014BA	0E				897+	DC	HL1' 14' cc failed mask
000014BB	E5C3E5C4	40404040			898+	DC	CL8' VCVD' instruction name
000014C4	00000010				899+	DC	A(16) result length
000014C8	000014F0				900+REA10	DC	A(RE10) result address
					901+*		INSTRUCTION UNDER TEST ROUTINE
000014CC					902+X10	DS	OF
000014CC	E710 8F48 0006			00001148	903+	VL	V1, V1FUDGE pollute V1
000014D2	E320 5050 0004			00001500	904+	LG	R2, RE10+16 get R2 source
000014D8	E612 0018 9058				905+	VCVD	V1, R2, 137, 1 test instruction
000014DE	E710 8F10 000E			00001110	906+	VST	V1, V1OUTPUT save
000014E4	B98D 0020				907+	EPSW	R2, R0 exptract psw
000014E8	5020 8EE8			000010E8	908+	ST	R2, CCPSW to save CC
000014EC	07FB				909+	BR	R11 return
000014F0					910+RE10	DC	OF
000014F0					911+	DROP	R5
000014F0	00000000	00000000			912	DC	XL16' 000000000000000000000000147483648D' V1 result t
000014F8	00000014	7483648D					
00001500	FFFFFFFF	80000000			913	DC	FD' - 2147483648'
					914		
					915 *		
					916 * VCVD		m4= 3 (LB=0, P1=1 , CS=1)
					917 *		i3= 159 (IOM=1, RDC=31)
					918		
					919	VRR_K	VCVD, 159, 3, 0
00001508					920+	DS	OFD
00001508			00001508		921+	USING	*, R5 base for test data and test routine
00001508	00001524				922+T11	DC	A(X11) address of test routine
0000150C	000B				923+	DC	H' 11' test number
0000150E	00				924+	DC	XL1' 00'
0000150F	9F				925+	DC	HL1' 159' i3
00001510	03				926+	DC	HL1' 3' m4
00001511	00				927+	DC	HL1' 0' cc
00001512	07				928+	DC	HL1' 7' cc failed mask
00001513	E5C3E5C4	40404040			929+	DC	CL8' VCVD' instruction name
0000151C	00000010				930+	DC	A(16) result length
00001520	00001548				931+REA11	DC	A(RE11) result address
					932+*		INSTRUCTION UNDER TEST ROUTINE
00001524					933+X11	DS	OF
00001524	E710 8F48 0006			00001148	934+	VL	V1, V1FUDGE pollute V1
0000152A	E320 5050 0004			00001558	935+	LG	R2, RE11+16 get R2 source
00001530	E612 0039 F058				936+	VCVD	V1, R2, 159, 3 test instruction

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001536	E710 8F10 000E		00001110	937+	VST	V1, V10OUTPUT	save	
0000153C	B98D 0020			938+	EPSW	R2, R0	exptrect psw	
00001540	5020 8EE8		000010E8	939+	ST	R2, CCPSW	to save CC	
00001544	07FB			940+	BR	R11	return	
00001548				941+RE11	DC	0F		
00001548				942+	DROP	R5		
00001548	00000000 00000000			943	DC	XL16' 00000000000000000000000000000000F'	V1 result	
00001550	00000000 0000000F							
00001558	00000000 00000000			944	DC	FD' 0'	R2 source	
				945				
				946	VRR_K	VCVD, 159, 3, 0		
00001560				947+	DS	0FD		
00001560		00001560		948+	USING	*, R5	base for test data and test routine	
00001560	0000157C			949+T12	DC	A(X12)	address of test routine	
00001564	000C			950+	DC	H' 12'	test number	
00001566	00			951+	DC	XL1' 00'		
00001567	9F			952+	DC	HL1' 159'	i3	
00001568	03			953+	DC	HL1' 3'	m4	
00001569	00			954+	DC	HL1' 0'	cc	
0000156A	07			955+	DC	HL1' 7'	cc failed mask	
0000156B	E5C3E5C4 40404040			956+	DC	CL8' VCVD'	instruction name	
00001574	00000010			957+	DC	A(16)	result length	
00001578	000015A0			958+REA12	DC	A(RE12)	result address	
				959+*			INSTRUCTION UNDER TEST ROUTINE	
0000157C				960+X12	DS	0F		
0000157C	E710 8F48 0006		00001148	961+	VL	V1, V1FUDGE	pollute V1	
00001582	E320 5050 0004		000015B0	962+	LG	R2, RE12+16	get R2 source	
00001588	E612 0039 F058			963+	VCVD	V1, R2, 159, 3	test instruction	
0000158E	E710 8F10 000E		00001110	964+	VST	V1, V10OUTPUT	save	
00001594	B98D 0020			965+	EPSW	R2, R0	exptrect psw	
00001598	5020 8EE8		000010E8	966+	ST	R2, CCPSW	to save CC	
0000159C	07FB			967+	BR	R11	return	
000015A0				968+RE12	DC	0F		
000015A0				969+	DROP	R5		
000015A0	00000000 00000000			970	DC	XL16' 000000000000000000000000000000001F'	V1 result	
000015A8	00000000 0000001F							
000015B0	00000000 00000001			971	DC	FD' 1'	R2 source	
				972				
				973	VRR_K	VCVD, 159, 3, 0		
000015B8				974+	DS	0FD		
000015B8		000015B8		975+	USING	*, R5	base for test data and test routine	
000015B8	000015D4			976+T13	DC	A(X13)	address of test routine	
000015BC	000D			977+	DC	H' 13'	test number	
000015BE	00			978+	DC	XL1' 00'		
000015BF	9F			979+	DC	HL1' 159'	i3	
000015C0	03			980+	DC	HL1' 3'	m4	
000015C1	00			981+	DC	HL1' 0'	cc	
000015C2	07			982+	DC	HL1' 7'	cc failed mask	
000015C3	E5C3E5C4 40404040			983+	DC	CL8' VCVD'	instruction name	
000015CC	00000010			984+	DC	A(16)	result length	
000015D0	000015F8			985+REA13	DC	A(RE13)	result address	
				986+*			INSTRUCTION UNDER TEST ROUTINE	
000015D4				987+X13	DS	0F		
000015D4	E710 8F48 0006		00001148	988+	VL	V1, V1FUDGE	pollute V1	
000015DA	E320 5050 0004		00001608	989+	LG	R2, RE13+16	get R2 source	
000015E0	E612 0039 F058			990+	VCVD	V1, R2, 159, 3	test instruction	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001696	E710 8F10 000E		00001110	1045+	VST	V1, V10OUTPUT	save
0000169C	B98D 0020			1046+	EPSW	R2, R0	exptract psw
000016A0	5020 8EE8		000010E8	1047+	ST	R2, CCPSW	to save CC
000016A4	07FB			1048+	BR	R11	return
000016A8				1049+RE15	DC	0F	
000016A8				1050+	DROP	R5	
000016A8	00000000 00000000			1051	DC	XL16' 000000000000000000000002147483648F'	V1 result
000016B0	00000214 7483648F						
000016B8	FFFFFFFF 80000000			1052	DC	FD' - 2147483648'	R2 source
				1053			
				1054 * VCVD		m4= 3 (LB=0, P1=1 , CS=1)	
				1055 *		i3= 137 (IOM=1, RDC= 9)	
				1056			
				1057	VRR_K	VCVD, 137, 3, 0	
000016C0				1058+	DS	0FD	
000016C0		000016C0		1059+	USING	*, R5	base for test data and test routine
000016C0	000016DC			1060+T16	DC	A(X16)	address of test routine
000016C4	0010			1061+	DC	H' 16'	test number
000016C6	00			1062+	DC	XL1' 00'	
000016C7	89			1063+	DC	HL1' 137'	i3
000016C8	03			1064+	DC	HL1' 3'	m4
000016C9	00			1065+	DC	HL1' 0'	cc
000016CA	07			1066+	DC	HL1' 7'	cc failed mask
000016CB	E5C3E5C4 40404040			1067+	DC	CL8' VCVD'	instruction name
000016D4	00000010			1068+	DC	A(16)	result length
000016D8	00001700			1069+REA16	DC	A(RE16)	result address
				1070+*			INSTRUCTION UNDER TEST ROUTINE
000016DC				1071+X16	DS	0F	
000016DC	E710 8F48 0006		00001148	1072+	VL	V1, V1FUDGE	pollute V1
000016E2	E320 5050 0004		00001710	1073+	LG	R2, RE16+16	get R2 source
000016E8	E612 0038 9058			1074+	VCVD	V1, R2, 137, 3	test instruction
000016EE	E710 8F10 000E		00001110	1075+	VST	V1, V10OUTPUT	save
000016F4	B98D 0020			1076+	EPSW	R2, R0	exptract psw
000016F8	5020 8EE8		000010E8	1077+	ST	R2, CCPSW	to save CC
000016FC	07FB			1078+	BR	R11	return
00001700				1079+RE16	DC	0F	
00001700				1080+	DROP	R5	
00001700	00000000 00000000			1081	DC	XL16' 0000000000000000000000000000000F'	V1 result
00001708	00000000 0000000F						
00001710	00000000 00000000			1082	DC	FD' 0'	R2 source
				1083			
				1084	VRR_K	VCVD, 137, 3, 0	
00001718				1085+	DS	0FD	
00001718		00001718		1086+	USING	*, R5	base for test data and test routine
00001718	00001734			1087+T17	DC	A(X17)	address of test routine
0000171C	0011			1088+	DC	H' 17'	test number
0000171E	00			1089+	DC	XL1' 00'	
0000171F	89			1090+	DC	HL1' 137'	i3
00001720	03			1091+	DC	HL1' 3'	m4
00001721	00			1092+	DC	HL1' 0'	cc
00001722	07			1093+	DC	HL1' 7'	cc failed mask
00001723	E5C3E5C4 40404040			1094+	DC	CL8' VCVD'	instruction name
0000172C	00000010			1095+	DC	A(16)	result length
00001730	00001758			1096+REA17	DC	A(RE17)	result address
				1097+*			INSTRUCTION UNDER TEST ROUTINE
00001734				1098+X17	DS	0F	

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LOC	OBJECT CODE		ADDR1	ADDR2	STMT		
0000188C	00000010				1207+	DC	A(16)
00001890	000018B8				1208+REA21	DC	A(RE21)
					1209+*		result length
					1210+X21	DS	0F
00001894	E710 8F48 0006			00001148	1211+	VL	V1, V1FUDGE
00001894	E320 5050 0004			000018C8	1212+	LG	R2, RE21+16
000018A0	E612 0099 F058				1213+	VCVD	V1, R2, 159, 9
000018A6	E710 8F10 000E			00001110	1214+	VST	V1, V10UTPUT
000018AC	B98D 0020				1215+	EPSW	R2, R0
000018B0	5020 8EE8			000010E8	1216+	ST	R2, CCPSW
000018B4	07FB				1217+	BR	R11
000018B8					1218+RE21	DC	0F
000018B8					1219+	DROP	R5
000018B8	00000000 00000000				1220	DC	XL16' 00000000000000000000000000000000C'
000018C0	00000000 0000000C						V1 result
000018C8	00000000 00000000				1221	DC	FD' 0'
					1222		R2 source
					1223	VRR_K	VCVD, 159, 9, 0
000018D0					1224+	DS	0FD
000018D0			000018D0		1225+	USING	*, R5
000018D0	000018EC				1226+T22	DC	A(X22)
000018D4	0016				1227+	DC	H' 22'
000018D6	00				1228+	DC	XL1' 00'
000018D7	9F				1229+	DC	HL1' 159'
000018D8	09				1230+	DC	HL1' 9'
000018D9	00				1231+	DC	HL1' 0'
000018DA	07				1232+	DC	HL1' 7'
000018DB	E5C3E5C4 40404040				1233+	DC	CL8' VCVD'
000018E4	00000010				1234+	DC	A(16)
000018E8	00001910				1235+REA22	DC	A(RE22)
					1236+*		result address
					1237+X22	DS	0F
000018EC					1238+	VL	V1, V1FUDGE
000018EC	E710 8F48 0006			00001148	1239+	LG	R2, RE22+16
000018F2	E320 5050 0004			00001920	1240+	VCVD	V1, R2, 159, 9
000018F8	E612 0099 F058				1241+	VST	V1, V10UTPUT
000018FE	E710 8F10 000E			00001110	1242+	EPSW	R2, R0
00001904	B98D 0020				1243+	ST	R2, CCPSW
00001908	5020 8EE8			000010E8	1244+	BR	R11
0000190C	07FB				1245+RE22	DC	0F
00001910					1246+	DROP	R5
00001910	00000000 00000000				1247	DC	XL16' 000000000000000000000000000000001C'
00001918	00000000 0000001C						V1 result
00001920	00000000 00000001				1248	DC	FD' 1'
					1249		R2 source
					1250	VRR_K	VCVD, 159, 9, 0
00001928					1251+	DS	0FD
00001928			00001928		1252+	USING	*, R5
00001928	00001944				1253+T23	DC	A(X23)
0000192C	0017				1254+	DC	H' 23'
0000192E	00				1255+	DC	XL1' 00'
0000192F	9F				1256+	DC	HL1' 159'
00001930	09				1257+	DC	HL1' 9'
00001931	00				1258+	DC	HL1' 0'
00001932	07				1259+	DC	HL1' 7'
00001933	E5C3E5C4 40404040				1260+	DC	CL8' VCVD'
							cc failed mask
							instruction name
							UINT_MAX
							base for test data and test routine
							address of test routine
							test number
							i3
							m4
							cc
							pollute V1
							get R2 source
							test instruction
							save
							exptract psw
							to save CC
							return

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000193C	00000010			1261+	DC	A(16)	result length
00001940	00001968			1262+REA23	DC	A(RE23)	result address
				1263+*			INSTRUCTION UNDER TEST ROUTINE
00001944				1264+X23	DS	0F	
00001944	E710 8F48 0006		00001148	1265+	VL	V1, V1FUDGE	pollute V1
0000194A	E320 5050 0004		00001978	1266+	LG	R2, RE23+16	get R2 source
00001950	E612 0099 F058			1267+	VCVD	V1, R2, 159, 9	test instruction
00001956	E710 8F10 000E		00001110	1268+	VST	V1, V10UTPUT	save
0000195C	B98D 0020			1269+	EPSW	R2, R0	exptract psw
00001960	5020 8EE8		000010E8	1270+	ST	R2, CCPSW	to save CC
00001964	07FB			1271+	BR	R11	return
00001968				1272+RE23	DC	0F	
00001968				1273+	DROP	R5	
00001968	00000000 00000000			1274	DC	XL16' 0000000000000000000000004294967295C'	V1 result
00001970	00000429 4967295C						
00001978	FFFFFFFF FFFFFFFF			1275	DC	FD' - 1'	R2 source
				1276			
				1277	VRR_K	VCVD, 159, 9, 0	INT_MAX
00001980				1278+	DS	0FD	
00001980		00001980		1279+	USING	*, R5	base for test data and test routine
00001980	0000199C			1280+T24	DC	A(X24)	address of test routine
00001984	0018			1281+	DC	H' 24'	test number
00001986	00			1282+	DC	XL1' 00'	
00001987	9F			1283+	DC	HL1' 159'	i3
00001988	09			1284+	DC	HL1' 9'	m4
00001989	00			1285+	DC	HL1' 0'	cc
0000198A	07			1286+	DC	HL1' 7'	cc failed mask
0000198B	E5C3E5C4 40404040			1287+	DC	CL8' VCVD'	instruction name
00001994	00000010			1288+	DC	A(16)	result length
00001998	000019C0			1289+REA24	DC	A(RE24)	result address
				1290+*			INSTRUCTION UNDER TEST ROUTINE
0000199C				1291+X24	DS	0F	
0000199C	E710 8F48 0006		00001148	1292+	VL	V1, V1FUDGE	pollute V1
000019A2	E320 5050 0004		000019D0	1293+	LG	R2, RE24+16	get R2 source
000019A8	E612 0099 F058			1294+	VCVD	V1, R2, 159, 9	test instruction
000019AE	E710 8F10 000E		00001110	1295+	VST	V1, V10UTPUT	save
000019B4	B98D 0020			1296+	EPSW	R2, R0	exptract psw
000019B8	5020 8EE8		000010E8	1297+	ST	R2, CCPSW	to save CC
000019BC	07FB			1298+	BR	R11	return
000019C0				1299+RE24	DC	0F	
000019C0				1300+	DROP	R5	
000019C0	00000000 00000000			1301	DC	XL16' 0000000000000000000000002147483647C'	V1 result
000019C8	00000214 7483647C						
000019D0	00000000 7FFFFFFF			1302	DC	FD' 2147483647'	R2 source
				1303			
				1304	VRR_K	VCVD, 159, 9, 0	INT_MIN
000019D8				1305+	DS	0FD	
000019D8		000019D8		1306+	USING	*, R5	base for test data and test routine
000019D8	000019F4			1307+T25	DC	A(X25)	address of test routine
000019DC	0019			1308+	DC	H' 25'	test number
000019DE	00			1309+	DC	XL1' 00'	
000019DF	9F			1310+	DC	HL1' 159'	i3
000019E0	09			1311+	DC	HL1' 9'	m4
000019E1	00			1312+	DC	HL1' 0'	cc
000019E2	07			1313+	DC	HL1' 7'	cc failed mask
000019E3	E5C3E5C4 40404040			1314+	DC	CL8' VCVD'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
00001A91	00			1369+ DC HL1' 0'
00001A92	07			1370+ DC HL1' 7'
00001A93	E5C3E5C4 40404040			1371+ DC CL8' VCVD'
00001A9C	00000010			1372+ DC A(16)
00001AA0	00001AC8			1373+REA27 DC A(RE27)
00001AA4				1374+*
00001AA4	E710 8F48 0006	00001148		1375+X27 DS OF
00001AAA	E320 5050 0004	00001AD8		1376+ VL V1, V1FUDGE
00001AB0	E612 0098 9058			1377+ LG R2, RE27+16
00001AB6	E710 8F10 000E	00001110		1378+ VCVD V1, R2, 137, 9
00001ABC	B98D 0020			1379+ VST V1, V1OUTPUT
00001AC0	5020 8EE8	000010E8		1380+ EPSW R2, R0
00001AC4	07FB			1381+ ST R2, CCPSW
00001AC8				1382+ BR R11
00001AC8				1383+RE27 DC OF
00001AC8				1384+ DROP R5
00001AC8	00000000 00000000			1385 DC XL16' 00000000000000000000000000000001C'
00001AD0	00000000 0000001C			
00001AD8	00000000 00000001			1386 DC FD' 1'
00001AE0				1387
00001AE0		00001AE0		1388 VRR_K VCVD, 137, 9, 3
00001AE0	00001AFC			1389+ DS OFD
00001AE4	001C			1390+ USING *, R5
00001AE6	00			1391+T28 DC A(X28)
00001AE7	89			1392+ DC H' 28'
00001AE8	09			1393+ DC XL1' 00'
00001AE9	03			1394+ DC HL1' 137'
00001AEA	0E			1395+ DC HL1' 9'
00001AEB	E5C3E5C4 40404040			1396+ DC HL1' 3'
00001AF4	00000010			1397+ DC HL1' 14'
00001AF8	00001B20			1398+ DC CL8' VCVD'
00001B00				1399+ DC A(16)
00001B04				1400+REA28 DC A(RE28)
00001B08				1401+*
00001B0C				1402+X28 DS OF
00001B10	E710 8F48 0006	00001148		1403+ VL V1, V1FUDGE
00001B14	E320 5050 0004	00001B30		1404+ LG R2, RE28+16
00001B18	E612 0098 9058			1405+ VCVD V1, R2, 137, 9
00001B1C	E710 8F10 000E	00001110		1406+ VST V1, V1OUTPUT
00001B20	B98D 0020			1407+ EPSW R2, R0
00001B24	5020 8EE8	000010E8		1408+ ST R2, CCPSW
00001B28	07FB			1409+ BR R11
00001B2C				1410+RE28 DC OF
00001B30				1411+ DROP R5
00001B34	00000000 00000000			1412 DC XL16' 0000000000000000000000000294967295C'
00001B38	00000029 4967295C			
00001B3C	FFFFFFFF FFFFFFFF			1413 DC FD' - 1'
00001B40				1414
00001B44				1415 VRR_K VCVD, 137, 9, 3
00001B48		00001B38		1416+ DS OFD
00001B4C	00001B54			1417+ USING *, R5
00001B50	001D			1418+T29 DC A(X29)
00001B54	00			1419+ DC H' 29'
00001B58	89			1420+ DC XL1' 00'
00001B5C	09			1421+ DC HL1' 137'
00001B60				1422+ DC HL1' 9'

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT			
00001B41	03				1423+	DC	HL1' 3'	cc
00001B42	0E				1424+	DC	HL1' 14'	cc failed mask
00001B43	E5C3E5C4	40404040			1425+	DC	CL8' VCVD'	instruction name
00001B4C	00000010				1426+	DC	A(16)	result length
00001B50	00001B78				1427+REA29	DC	A(RE29)	result address
					1428+*			INSTRUCTION UNDER TEST ROUTINE
00001B54					1429+X29	DS	OF	
00001B54	E710	8F48	0006	00001148	1430+	VL	V1, V1FUDGE	pollute V1
00001B5A	E320	5050	0004	00001B88	1431+	LG	R2, RE29+16	get R2 source
00001B60	E612	0098	9058		1432+	VCVD	V1, R2, 137, 9	test instruction
00001B66	E710	8F10	000E	00001110	1433+	VST	V1, V10UTPUT	save
00001B6C	B98D	0020			1434+	EPSW	R2, R0	exptract psw
00001B70	5020	8EE8		000010E8	1435+	ST	R2, CCPSW	to save CC
00001B74	07FB				1436+	BR	R11	return
00001B78					1437+RE29	DC	OF	
00001B78					1438+	DROP	R5	
00001B78	00000000	00000000			1439	DC	XL16' 000000000000000000000000147483647C'	V1 result t
00001B80	00000014	7483647C						
00001B88	00000000	7FFFFFFF			1440	DC	FD' 2147483647'	R2 source
					1441			
					1442	VRR_K	VCVD, 137, 9, 3	INT_MIN
00001B90					1443+	DS	OFD	
00001B90			00001B90		1444+	USING	*, R5	base for test data and test routine
00001B90	00001BAC				1445+T30	DC	A(X30)	address of test routine
00001B94	001E				1446+	DC	H' 30'	test number
00001B96	00				1447+	DC	XL1' 00'	
00001B97	89				1448+	DC	HL1' 137'	i3
00001B98	09				1449+	DC	HL1' 9'	m4
00001B99	03				1450+	DC	HL1' 3'	cc
00001B9A	0E				1451+	DC	HL1' 14'	cc failed mask
00001B9B	E5C3E5C4	40404040			1452+	DC	CL8' VCVD'	instruction name
00001BA4	00000010				1453+	DC	A(16)	result length
00001BA8	00001BD0				1454+REA30	DC	A(RE30)	result address
					1455+*			INSTRUCTION UNDER TEST ROUTINE
00001BAC					1456+X30	DS	OF	
00001BAC	E710	8F48	0006	00001148	1457+	VL	V1, V1FUDGE	pollute V1
00001BB2	E320	5050	0004	00001BE0	1458+	LG	R2, RE30+16	get R2 source
00001BB8	E612	0098	9058		1459+	VCVD	V1, R2, 137, 9	test instruction
00001BBE	E710	8F10	000E	00001110	1460+	VST	V1, V10UTPUT	save
00001BC4	B98D	0020			1461+	EPSW	R2, R0	exptract psw
00001BC8	5020	8EE8		000010E8	1462+	ST	R2, CCPSW	to save CC
00001BCC	07FB				1463+	BR	R11	return
00001BD0					1464+RE30	DC	OF	
00001BD0					1465+	DROP	R5	
00001BD0	00000000	00000000			1466	DC	XL16' 000000000000000000000000147483648C'	V1 result t
00001BD8	00000014	7483648C						
00001BE0	FFFFFFFF	80000000			1467	DC	FD' - 2147483648'	
					1468			
					1469 *			
					1470 * VCVD		m4= 11 (LB=1, P1=1 , CS=1)	
					1471 *		i3= 159 (IOM=1, RDC=31)	
					1472			
					1473	VRR_K	VCVD, 159, 11, 0	
00001BE8					1474+	DS	OFD	
00001BE8			00001BE8		1475+	USING	*, R5	base for test data and test routine
00001BE8	00001C04				1476+T31	DC	A(X31)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00001BEC	001F			1477+	DC	H' 31' test number
00001BEE	00			1478+	DC	XL1' 00'
00001BEF	9F			1479+	DC	HL1' 159' i3
00001BF0	0B			1480+	DC	HL1' 11' m4
00001BF1	00			1481+	DC	HL1' 0' cc
00001BF2	07			1482+	DC	HL1' 7' cc failed mask
00001BF3	E5C3E5C4 40404040			1483+	DC	CL8' VCVD' instruction name
00001BFC	00000010			1484+	DC	A(16) result length
00001C00	00001C28			1485+REA31	DC	A(RE31) result address
				1486+*		INSTRUCTION UNDER TEST ROUTINE
00001C04				1487+X31	DS	0F
00001C04	E710 8F48 0006		00001148	1488+	VL	V1, V1FUDGE pollute V1
00001C0A	E320 5050 0004		00001C38	1489+	LG	R2, RE31+16 get R2 source
00001C10	E612 00B9 F058			1490+	VCVD	V1, R2, 159, 11 test instruction
00001C16	E710 8F10 000E		00001110	1491+	VST	V1, V10UTPUT save
00001C1C	B98D 0020			1492+	EPSW	R2, R0 exptract psw
00001C20	5020 8EE8		000010E8	1493+	ST	R2, CCPSW to save CC
00001C24	07FB			1494+	BR	R11 return
00001C28				1495+RE31	DC	0F
00001C28				1496+	DROP	R5
00001C28	00000000 00000000			1497	DC	XL16' 00000000000000000000000000000000F' V1 result
00001C30	00000000 0000000F					
00001C38	00000000 00000000			1498	DC	FD' 0' R2 source
				1499		
				1500	VRR_K	VCVD, 159, 11, 0
00001C40				1501+	DS	0FD
00001C40		00001C40		1502+	USING	*, R5 base for test data and test routine
00001C40	00001C5C			1503+T32	DC	A(X32) address of test routine
00001C44	0020			1504+	DC	H' 32' test number
00001C46	00			1505+	DC	XL1' 00'
00001C47	9F			1506+	DC	HL1' 159' i3
00001C48	0B			1507+	DC	HL1' 11' m4
00001C49	00			1508+	DC	HL1' 0' cc
00001C4A	07			1509+	DC	HL1' 7' cc failed mask
00001C4B	E5C3E5C4 40404040			1510+	DC	CL8' VCVD' instruction name
00001C54	00000010			1511+	DC	A(16) result length
00001C58	00001C80			1512+REA32	DC	A(RE32) result address
				1513+*		INSTRUCTION UNDER TEST ROUTINE
00001C5C				1514+X32	DS	0F
00001C5C	E710 8F48 0006		00001148	1515+	VL	V1, V1FUDGE pollute V1
00001C62	E320 5050 0004		00001C90	1516+	LG	R2, RE32+16 get R2 source
00001C68	E612 00B9 F058			1517+	VCVD	V1, R2, 159, 11 test instruction
00001C6E	E710 8F10 000E		00001110	1518+	VST	V1, V10UTPUT save
00001C74	B98D 0020			1519+	EPSW	R2, R0 exptract psw
00001C78	5020 8EE8		000010E8	1520+	ST	R2, CCPSW to save CC
00001C7C	07FB			1521+	BR	R11 return
00001C80				1522+RE32	DC	0F
00001C80				1523+	DROP	R5
00001C80	00000000 00000000			1524	DC	XL16' 000000000000000000000000000000001F' V1 result
00001C88	00000000 0000001F					
00001C90	00000000 00000001			1525	DC	FD' 1' R2 source
				1526		
				1527	VRR_K	VCVD, 159, 11, 0 UINT_MAX
00001C98				1528+	DS	0FD
00001C98		00001C98		1529+	USING	*, R5 base for test data and test routine
00001C98	00001CB4			1530+T33	DC	A(X33) address of test routine

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LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C9C	0021			1531+	DC	H' 33'	test number
00001C9E	00			1532+	DC	XL1' 00'	
00001C9F	9F			1533+	DC	HL1' 159'	i3
00001CA0	0B			1534+	DC	HL1' 11'	m4
00001CA1	00			1535+	DC	HL1' 0'	cc
00001CA2	07			1536+	DC	HL1' 7'	cc failed mask
00001CA3	E5C3E5C4 40404040			1537+	DC	CL8' VCVD'	instruction name
00001CAC	00000010			1538+	DC	A(16)	result length
00001CB0	00001CD8			1539+REA33	DC	A(RE33)	result address
				1540+*			INSTRUCTION UNDER TEST ROUTINE
00001CB4				1541+X33	DS	0F	
00001CB4	E710 8F48 0006		00001148	1542+	VL	V1, V1FUDGE	pollute V1
00001CBA	E320 5050 0004		00001CE8	1543+	LG	R2, RE33+16	get R2 source
00001CC0	E612 00B9 F058			1544+	VCVD	V1, R2, 159, 11	test instruction
00001CC6	E710 8F10 000E		00001110	1545+	VST	V1, V10UTPUT	save
00001CCC	B98D 0020			1546+	EPSW	R2, R0	exptract psw
00001CD0	5020 8EE8		000010E8	1547+	ST	R2, CCPSW	to save CC
00001CD4	07FB			1548+	BR	R11	return
00001CD8				1549+RE33	DC	0F	
00001CD8				1550+	DROP	R5	
00001CD8	00000000 00000000			1551	DC	XL16' 0000000000000000000000004294967295F'	V1 result
00001CE0	00000429 4967295F						
00001CE8	FFFFFFFF FFFFFFFF			1552	DC	FD' - 1'	R2 source
				1553			
				1554	VRR_K	VCVD, 159, 11, 0	INT_MAX
00001CF0				1555+	DS	0FD	
00001CF0		00001CF0		1556+	USING	*, R5	base for test data and test routine
00001CF0	00001D0C			1557+T34	DC	A(X34)	address of test routine
00001CF4	0022			1558+	DC	H' 34'	test number
00001CF6	00			1559+	DC	XL1' 00'	
00001CF7	9F			1560+	DC	HL1' 159'	i3
00001CF8	0B			1561+	DC	HL1' 11'	m4
00001CF9	00			1562+	DC	HL1' 0'	cc
00001CFA	07			1563+	DC	HL1' 7'	cc failed mask
00001CFB	E5C3E5C4 40404040			1564+	DC	CL8' VCVD'	instruction name
00001D04	00000010			1565+	DC	A(16)	result length
00001D08	00001D30			1566+REA34	DC	A(RE34)	result address
				1567+*			INSTRUCTION UNDER TEST ROUTINE
00001D0C				1568+X34	DS	0F	
00001D0C	E710 8F48 0006		00001148	1569+	VL	V1, V1FUDGE	pollute V1
00001D12	E320 5050 0004		00001D40	1570+	LG	R2, RE34+16	get R2 source
00001D18	E612 00B9 F058			1571+	VCVD	V1, R2, 159, 11	test instruction
00001D1E	E710 8F10 000E		00001110	1572+	VST	V1, V10UTPUT	save
00001D24	B98D 0020			1573+	EPSW	R2, R0	exptract psw
00001D28	5020 8EE8		000010E8	1574+	ST	R2, CCPSW	to save CC
00001D2C	07FB			1575+	BR	R11	return
00001D30				1576+RE34	DC	0F	
00001D30				1577+	DROP	R5	
00001D30	00000000 00000000			1578	DC	XL16' 0000000000000000000000002147483647F'	V1 result
00001D38	00000214 7483647F						
00001D40	00000000 7FFFFFFF			1579	DC	FD' 2147483647'	R2 source
				1580			
				1581	VRR_K	VCVD, 159, 11, 0	INT_MIN
00001D48				1582+	DS	0FD	
00001D48		00001D48		1583+	USING	*, R5	base for test data and test routine
00001D48	00001D64			1584+T35	DC	A(X35)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001D4C	0023			1585+	DC	H' 35'	test number
00001D4E	00			1586+	DC	XL1' 00'	
00001D4F	9F			1587+	DC	HL1' 159'	i3
00001D50	0B			1588+	DC	HL1' 11'	m4
00001D51	00			1589+	DC	HL1' 0'	cc
00001D52	07			1590+	DC	HL1' 7'	cc failed mask
00001D53	E5C3E5C4 40404040			1591+	DC	CL8' VCVD'	instruction name
00001D5C	00000010			1592+	DC	A(16)	result length
00001D60	00001D88			1593+REA35	DC	A(RE35)	result address
				1594+*			INSTRUCTION UNDER TEST ROUTINE
00001D64				1595+X35	DS	0F	
00001D64	E710 8F48 0006		00001148	1596+	VL	V1, V1FUDGE	pollute V1
00001D6A	E320 5050 0004		00001D98	1597+	LG	R2, RE35+16	get R2 source
00001D70	E612 00B9 F058			1598+	VCVD	V1, R2, 159, 11	test instruction
00001D76	E710 8F10 000E		00001110	1599+	VST	V1, V10UTPUT	save
00001D7C	B98D 0020			1600+	EPSW	R2, R0	exptract psw
00001D80	5020 8EE8		000010E8	1601+	ST	R2, CCPSW	to save CC
00001D84	07FB			1602+	BR	R11	return
00001D88				1603+RE35	DC	0F	
00001D88				1604+	DROP	R5	
00001D88	00000000 00000000			1605	DC	XL16' 0000000000000000000000002147483648F'	V1 result
00001D90	00000214 7483648F						
00001D98	FFFFFFFF 80000000			1606	DC	FD' - 2147483648'	R2 source
				1607			
				1608 * VCVD		m4= 11 (LB=1, P1=1 , CS=1)	
				1609 *		i3= 137 (IOM=1, RDC= 9)	
				1610			
				1611	VRR_K	VCVD, 137, 11, 0	
00001DA0				1612+	DS	0FD	
00001DA0		00001DA0		1613+	USING	*, R5	base for test data and test routine
00001DA0	00001DBC			1614+T36	DC	A(X36)	address of test routine
00001DA4	0024			1615+	DC	H' 36'	test number
00001DA6	00			1616+	DC	XL1' 00'	
00001DA7	89			1617+	DC	HL1' 137'	i3
00001DA8	0B			1618+	DC	HL1' 11'	m4
00001DA9	00			1619+	DC	HL1' 0'	cc
00001DAA	07			1620+	DC	HL1' 7'	cc failed mask
00001DAB	E5C3E5C4 40404040			1621+	DC	CL8' VCVD'	instruction name
00001DB4	00000010			1622+	DC	A(16)	result length
00001DB8	00001DE0			1623+REA36	DC	A(RE36)	result address
				1624+*			INSTRUCTION UNDER TEST ROUTINE
00001DBC				1625+X36	DS	0F	
00001DBC	E710 8F48 0006		00001148	1626+	VL	V1, V1FUDGE	pollute V1
00001DC2	E320 5050 0004		00001DF0	1627+	LG	R2, RE36+16	get R2 source
00001DC8	E612 00B8 9058			1628+	VCVD	V1, R2, 137, 11	test instruction
00001DCE	E710 8F10 000E		00001110	1629+	VST	V1, V10UTPUT	save
00001DD4	B98D 0020			1630+	EPSW	R2, R0	exptract psw
00001DD8	5020 8EE8		000010E8	1631+	ST	R2, CCPSW	to save CC
00001DDC	07FB			1632+	BR	R11	return
00001DE0				1633+RE36	DC	0F	
00001DE0				1634+	DROP	R5	
00001DE0	00000000 00000000			1635	DC	XL16' 00000000000000000000000000000000F'	V1 result
00001DE8	00000000 0000000F						
00001DF0	00000000 00000000			1636	DC	FD' 0'	R2 source
				1637			
				1638	VRR_K	VCVD, 137, 11, 0	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				1747 *-----	
				1748 * VCVDG - VECTOR CONVERT TO DECIMAL (64)	
				1749 *-----	
				1750 * VCVDG simple	m4= 1 (LB=0, P1=0 , CS=1)
				1751 *	m4= 3 (LB=0, P1=1 , CS=1)
				1752 *	m4= 9 (LB=1, P1=0 , CS=1)
				1753 *	m4= 11 (LB=1, P1=1 , CS=1)
				1754 *	
				1755 *	i3= 137 (IOM=1, RDC= 9)
				1756 *	i3= 159 (IOM=1, RDC=31)
				1757 *	
				1758 * VCVDG	m4= 1 (LB=0, P1=0 , CS=1)
				1759 *	i3= 159 (IOM=1, RDC=31)
				1760	
00001F58				1761	VRR_K VCVDG, 159, 1, 0
00001F58		00001F58		1762+	DS OFD
00001F58	00001F74			1763+	USING *, R5
00001F5C	0029			1764+T41	DC A(X41)
00001F5E	00			1765+	DC H' 41'
00001F5F	9F			1766+	DC XL1' 00'
00001F60	01			1767+	DC HL1' 159'
00001F61	00			1768+	DC HL1' 1'
00001F62	07			1769+	DC HL1' 0'
00001F63	E5C3E5C4 C7404040			1770+	DC HL1' 7'
00001F6C	00000010			1771+	DC CL8' VCVDG'
00001F70	00001F98			1772+	DC A(16)
				1773+REA41	DC A(RE41)
				1774+*	INSTRUCTION UNDER TEST ROUTINE
00001F74				1775+X41	DS OF
00001F74	E710 8F48 0006		00001148	1776+	VL V1, V1FUDGE
00001F7A	E320 5050 0004		00001FA8	1777+	LG R2, RE41+16
00001F80	E612 0019 F05A			1778+	VCVDG V1, R2, 159, 1
00001F86	E710 8F10 000E		00001110	1779+	VST V1, V10UTPUT
00001F8C	B98D 0020			1780+	EPSW R2, R0
00001F90	5020 8EE8		000010E8	1781+	ST R2, CCPSW
00001F94	07FB			1782+	BR R11
00001F98				1783+RE41	DC OF
00001F98				1784+	DROP R5
00001F98	00000000 00000000			1785	DC XL16' 000000000000000000000000000000C'
00001FA0	00000000 0000000C				V1 result
00001FA8	00000000 00000000			1786	DC FD' 0'
					R2 source
				1787	
				1788	VRR_K VCVDG, 159, 1, 0
00001FB0				1789+	DS OFD
00001FB0		00001FB0		1790+	USING *, R5
00001FB0	00001FCC			1791+T42	DC A(X42)
00001FB4	002A			1792+	DC H' 42'
00001FB6	00			1793+	DC XL1' 00'
00001FB7	9F			1794+	DC HL1' 159'
00001FB8	01			1795+	DC HL1' 1'
00001FB9	00			1796+	DC HL1' 0'
00001FBA	07			1797+	DC HL1' 7'
00001FBB	E5C3E5C4 C7404040			1798+	DC CL8' VCVDG'
00001FC4	00000010			1799+	DC A(16)
00001FC8	00001FF0			1800+REA42	DC A(RE42)
				1801+*	INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000207C				1856+X44	DS	0F	
0000207C	E710 8F48 0006		00001148	1857+	VL	V1, V1FUDGE	pollute V1
00002082	E320 5050 0004		000020B0	1858+	LG	R2, RE44+16	get R2 source
00002088	E612 0019 F05A			1859+	VCVDG	V1, R2, 159, 1	test instruction
0000208E	E710 8F10 000E		00001110	1860+	VST	V1, V10UTPUT	save
00002094	B98D 0020			1861+	EPSW	R2, R0	exptract psw
00002098	5020 8EE8		000010E8	1862+	ST	R2, CCPSW	to save CC
0000209C	07FB			1863+	BR	R11	return
000020A0				1864+RE44	DC	0F	
000020A0				1865+	DROP	R5	
000020A0	00000000 00000000			1866	DC	XL16' 0000000000000000000000002147483647C'	V1 result
000020A8	00000214 7483647C						
000020B0	00000000 7FFFFFFF			1867	DC	FD' 2147483647'	R2 source
				1868			
				1869	VRR_K	VCVDG, 159, 1, 0	INT_MIN
000020B8				1870+	DS	0FD	
000020B8		000020B8		1871+	USING	*, R5	base for test data and test routine
000020B8	000020D4			1872+T45	DC	A(X45)	address of test routine
000020BC	002D			1873+	DC	H' 45'	test number
000020BE	00			1874+	DC	XL1' 00'	
000020BF	9F			1875+	DC	HL1' 159'	i3
000020C0	01			1876+	DC	HL1' 1'	m4
000020C1	00			1877+	DC	HL1' 0'	cc
000020C2	07			1878+	DC	HL1' 7'	cc failed mask
000020C3	E5C3E5C4 C7404040			1879+	DC	CL8' VCVDG'	instruction name
000020CC	00000010			1880+	DC	A(16)	result length
000020D0	000020F8			1881+REA45	DC	A(RE45)	result address
				1882+*			INSTRUCTION UNDER TEST ROUTINE
000020D4				1883+X45	DS	0F	
000020D4	E710 8F48 0006		00001148	1884+	VL	V1, V1FUDGE	pollute V1
000020DA	E320 5050 0004		00002108	1885+	LG	R2, RE45+16	get R2 source
000020E0	E612 0019 F05A			1886+	VCVDG	V1, R2, 159, 1	test instruction
000020E6	E710 8F10 000E		00001110	1887+	VST	V1, V10UTPUT	save
000020EC	B98D 0020			1888+	EPSW	R2, R0	exptract psw
000020F0	5020 8EE8		000010E8	1889+	ST	R2, CCPSW	to save CC
000020F4	07FB			1890+	BR	R11	return
000020F8				1891+RE45	DC	0F	
000020F8				1892+	DROP	R5	
000020F8	00000000 00000000			1893	DC	XL16' 0000000000000000000000002147483648D'	V1 result
00002100	00000214 7483648D						
00002108	FFFFFFFF 80000000			1894	DC	FD' - 2147483648'	R2 source
				1895			
				1896	VRR_K	VCVDG, 159, 1, 0	LONG_MAX
00002110				1897+	DS	0FD	
00002110		00002110		1898+	USING	*, R5	base for test data and test routine
00002110	0000212C			1899+T46	DC	A(X46)	address of test routine
00002114	002E			1900+	DC	H' 46'	test number
00002116	00			1901+	DC	XL1' 00'	
00002117	9F			1902+	DC	HL1' 159'	i3
00002118	01			1903+	DC	HL1' 1'	m4
00002119	00			1904+	DC	HL1' 0'	cc
0000211A	07			1905+	DC	HL1' 7'	cc failed mask
0000211B	E5C3E5C4 C7404040			1906+	DC	CL8' VCVDG'	instruction name
00002124	00000010			1907+	DC	A(16)	result length
00002128	00002150			1908+REA46	DC	A(RE46)	result address
				1909+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000212C				1910+X46	DS	0F	
0000212C	E710 8F48 0006		00001148	1911+	VL	V1, V1FUDGE	pollute V1
00002132	E320 5050 0004		00002160	1912+	LG	R2, RE46+16	get R2 source
00002138	E612 0019 F05A			1913+	VCVDG	V1, R2, 159, 1	test instruction
0000213E	E710 8F10 000E		00001110	1914+	VST	V1, V10UTPUT	save
00002144	B98D 0020			1915+	EPSW	R2, R0	exptract psw
00002148	5020 8EE8		000010E8	1916+	ST	R2, CCPSW	to save CC
0000214C	07FB			1917+	BR	R11	return
00002150				1918+RE46	DC	0F	
00002150				1919+	DROP	R5	
00002150	00000000 00009223			1920	DC	XL16' 00000000000009223372036854775807C'	V1 source
00002158	37203685 4775807C						
00002160	7FFFFFFF FFFFFFFF			1921	DC	XL08' 7FFFFFFF'	R1 result
				1922			
				1923	VRR_K	VCVDG, 159, 1, 0	LONG_MIN
00002168				1924+	DS	0FD	
00002168		00002168		1925+	USING	*, R5	base for test data and test routine
00002168	00002184			1926+T47	DC	A(X47)	address of test routine
0000216C	002F			1927+	DC	H' 47'	test number
0000216E	00			1928+	DC	XL1' 00'	
0000216F	9F			1929+	DC	HL1' 159'	i3
00002170	01			1930+	DC	HL1' 1'	m4
00002171	00			1931+	DC	HL1' 0'	cc
00002172	07			1932+	DC	HL1' 7'	cc failed mask
00002173	E5C3E5C4 C7404040			1933+	DC	CL8' VCVDG'	instruction name
0000217C	00000010			1934+	DC	A(16)	result length
00002180	000021A8			1935+REA47	DC	A(RE47)	result address
				1936+*			INSTRUCTION UNDER TEST ROUTINE
00002184				1937+X47	DS	0F	
00002184	E710 8F48 0006		00001148	1938+	VL	V1, V1FUDGE	pollute V1
0000218A	E320 5050 0004		000021B8	1939+	LG	R2, RE47+16	get R2 source
00002190	E612 0019 F05A			1940+	VCVDG	V1, R2, 159, 1	test instruction
00002196	E710 8F10 000E		00001110	1941+	VST	V1, V10UTPUT	save
0000219C	B98D 0020			1942+	EPSW	R2, R0	exptract psw
000021A0	5020 8EE8		000010E8	1943+	ST	R2, CCPSW	to save CC
000021A4	07FB			1944+	BR	R11	return
000021A8				1945+RE47	DC	0F	
000021A8				1946+	DROP	R5	
000021A8	00000000 00009223			1947	DC	XL16' 00000000000009223372036854775808D'	V1 source
000021B0	37203685 4775808D						
000021B8	80000000 00000000			1948	DC	XL08' 8000000000000000'	R1 result
				1949			
				1950	VRR_K	VCVDG, 159, 1, 0	ULONG_MAX
000021C0				1951+	DS	0FD	
000021C0		000021C0		1952+	USING	*, R5	base for test data and test routine
000021C0	000021DC			1953+T48	DC	A(X48)	address of test routine
000021C4	0030			1954+	DC	H' 48'	test number
000021C6	00			1955+	DC	XL1' 00'	
000021C7	9F			1956+	DC	HL1' 159'	i3
000021C8	01			1957+	DC	HL1' 1'	m4
000021C9	00			1958+	DC	HL1' 0'	cc
000021CA	07			1959+	DC	HL1' 7'	cc failed mask
000021CB	E5C3E5C4 C7404040			1960+	DC	CL8' VCVDG'	instruction name
000021D4	00000010			1961+	DC	A(16)	result length
000021D8	00002200			1962+REA48	DC	A(RE48)	result address
				1963+*			INSTRUCTION UNDER TEST ROUTINE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000023E4	00000010			2126+	DC	A(16)	result length
000023E8	00002410			2127+REA54	DC	A(RE54)	result address
				2128+*			INSTRUCTION UNDER TEST ROUTINE
000023EC				2129+X54	DS	0F	
000023EC	E710 8F48 0006		00001148	2130+	VL	V1, V1FUDGE	pollute V1
000023F2	E320 5050 0004		00002420	2131+	LG	R2, RE54+16	get R2 source
000023F8	E612 0018 905A			2132+	VCVDG	V1, R2, 137, 1	test instruction
000023FE	E710 8F10 000E		00001110	2133+	VST	V1, V10UTPUT	save
00002404	B98D 0020			2134+	EPSW	R2, R0	exptract psw
00002408	5020 8EE8		000010E8	2135+	ST	R2, CCPSW	to save CC
0000240C	07FB			2136+	BR	R11	return
00002410				2137+RE54	DC	0F	
00002410				2138+	DROP	R5	
00002410	00000000 00000000			2139	DC	XL16' 000000000000000000000000854775807C'	V1 source
00002418	00000085 4775807C						
00002420	7FFFFFFF FFFFFFFF			2140	DC	XL08' 7FFFFFFF	R1 result
				2141			
				2142	VRR_K	VCVDG, 137, 1, 3	LONG_MIN
00002428				2143+	DS	0FD	
00002428		00002428		2144+	USING	*, R5	base for test data and test routine
00002428	00002444			2145+T55	DC	A(X55)	address of test routine
0000242C	0037			2146+	DC	H' 55'	test number
0000242E	00			2147+	DC	XL1' 00'	
0000242F	89			2148+	DC	HL1' 137'	i3
00002430	01			2149+	DC	HL1' 1'	m4
00002431	03			2150+	DC	HL1' 3'	cc
00002432	0E			2151+	DC	HL1' 14'	cc failed mask
00002433	E5C3E5C4 C7404040			2152+	DC	CL8' VCVDG'	instruction name
0000243C	00000010			2153+	DC	A(16)	result length
00002440	00002468			2154+REA55	DC	A(RE55)	result address
				2155+*			INSTRUCTION UNDER TEST ROUTINE
00002444				2156+X55	DS	0F	
00002444	E710 8F48 0006		00001148	2157+	VL	V1, V1FUDGE	pollute V1
0000244A	E320 5050 0004		00002478	2158+	LG	R2, RE55+16	get R2 source
00002450	E612 0018 905A			2159+	VCVDG	V1, R2, 137, 1	test instruction
00002456	E710 8F10 000E		00001110	2160+	VST	V1, V10UTPUT	save
0000245C	B98D 0020			2161+	EPSW	R2, R0	exptract psw
00002460	5020 8EE8		000010E8	2162+	ST	R2, CCPSW	to save CC
00002464	07FB			2163+	BR	R11	return
00002468				2164+RE55	DC	0F	
00002468				2165+	DROP	R5	
00002468	00000000 00000000			2166	DC	XL16' 000000000000000000000000854775808D'	V1 source
00002470	00000085 4775808D						
00002478	80000000 00000000			2167	DC	XL08' 800000000000000000000000'	R1 result
				2168			
				2169	VRR_K	VCVDG, 137, 1, 0	ULONG_MAX
00002480				2170+	DS	0FD	
00002480		00002480		2171+	USING	*, R5	base for test data and test routine
00002480	0000249C			2172+T56	DC	A(X56)	address of test routine
00002484	0038			2173+	DC	H' 56'	test number
00002486	00			2174+	DC	XL1' 00'	
00002487	89			2175+	DC	HL1' 137'	i3
00002488	01			2176+	DC	HL1' 1'	m4
00002489	00			2177+	DC	HL1' 0'	cc
0000248A	07			2178+	DC	HL1' 7'	cc failed mask
0000248B	E5C3E5C4 C7404040			2179+	DC	CL8' VCVDG'	instruction name

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000025E8	03			2288+	DC	HL1' 3'	m4
000025E9	00			2289+	DC	HL1' 0'	cc
000025EA	07			2290+	DC	HL1' 7'	cc failed mask
000025EB	E5C3E5C4 C7404040			2291+	DC	CL8' VCVDG'	instruction name
000025F4	00000010			2292+	DC	A(16)	result length
000025F8	00002620			2293+REA60	DC	A(RE60)	result address
				2294+*			INSTRUCTION UNDER TEST ROUTINE
000025FC				2295+X60	DS	0F	
000025FC	E710 8F48 0006		00001148	2296+	VL	V1, V1FUDGE	pollute V1
00002602	E320 5050 0004		00002630	2297+	LG	R2, RE60+16	get R2 source
00002608	E612 0039 F05A			2298+	VCVDG	V1, R2, 159, 3	test instruction
0000260E	E710 8F10 000E		00001110	2299+	VST	V1, V10UTPUT	save
00002614	B98D 0020			2300+	EPSW	R2, R0	exptract psw
00002618	5020 8EE8		000010E8	2301+	ST	R2, CCPSW	to save CC
0000261C	07FB			2302+	BR	R11	return
00002620				2303+RE60	DC	0F	
00002620				2304+	DROP	R5	
00002620	00000000 00000000			2305	DC	XL16' 00000000000000000000000002147483647F'	V1 result
00002628	00000214 7483647F						
00002630	00000000 7FFFFFFF			2306	DC	FD' 2147483647'	R2 source
				2307			
				2308	VRR_K	VCVDG, 159, 3, 0	INT_MIN
00002638				2309+	DS	0FD	
00002638		00002638		2310+	USING	*, R5	base for test data and test routine
00002638	00002654			2311+T61	DC	A(X61)	address of test routine
0000263C	003D			2312+	DC	H' 61'	test number
0000263E	00			2313+	DC	XL1' 00'	
0000263F	9F			2314+	DC	HL1' 159'	i3
00002640	03			2315+	DC	HL1' 3'	m4
00002641	00			2316+	DC	HL1' 0'	cc
00002642	07			2317+	DC	HL1' 7'	cc failed mask
00002643	E5C3E5C4 C7404040			2318+	DC	CL8' VCVDG'	instruction name
0000264C	00000010			2319+	DC	A(16)	result length
00002650	00002678			2320+REA61	DC	A(RE61)	result address
				2321+*			INSTRUCTION UNDER TEST ROUTINE
00002654				2322+X61	DS	0F	
00002654	E710 8F48 0006		00001148	2323+	VL	V1, V1FUDGE	pollute V1
0000265A	E320 5050 0004		00002688	2324+	LG	R2, RE61+16	get R2 source
00002660	E612 0039 F05A			2325+	VCVDG	V1, R2, 159, 3	test instruction
00002666	E710 8F10 000E		00001110	2326+	VST	V1, V10UTPUT	save
0000266C	B98D 0020			2327+	EPSW	R2, R0	exptract psw
00002670	5020 8EE8		000010E8	2328+	ST	R2, CCPSW	to save CC
00002674	07FB			2329+	BR	R11	return
00002678				2330+RE61	DC	0F	
00002678				2331+	DROP	R5	
00002678	00000000 00000000			2332	DC	XL16' 00000000000000000000000002147483648F'	V1 result
00002680	00000214 7483648F						
00002688	FFFFFFFF 80000000			2333	DC	FD' - 2147483648'	R2 source
				2334			
				2335	VRR_K	VCVDG, 159, 3, 0	LONG_MAX
00002690				2336+	DS	0FD	
00002690		00002690		2337+	USING	*, R5	base for test data and test routine
00002690	000026AC			2338+T62	DC	A(X62)	address of test routine
00002694	003E			2339+	DC	H' 62'	test number
00002696	00			2340+	DC	XL1' 00'	
00002697	9F			2341+	DC	HL1' 159'	i3

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002698	03			2342+	DC	HL1' 3'	m4
00002699	00			2343+	DC	HL1' 0'	cc
0000269A	07			2344+	DC	HL1' 7'	cc failed mask
0000269B	E5C3E5C4 C7404040			2345+	DC	CL8' VCVDG'	instruction name
000026A4	00000010			2346+	DC	A(16)	result length
000026A8	000026D0			2347+REA62	DC	A(RE62)	result address
				2348+*			INSTRUCTION UNDER TEST ROUTINE
000026AC				2349+X62	DS	0F	
000026AC	E710 8F48 0006		00001148	2350+	VL	V1, V1FUDGE	pollute V1
000026B2	E320 5050 0004		000026E0	2351+	LG	R2, RE62+16	get R2 source
000026B8	E612 0039 F05A			2352+	VCVDG	V1, R2, 159, 3	test instruction
000026BE	E710 8F10 000E		00001110	2353+	VST	V1, V10UTPUT	save
000026C4	B98D 0020			2354+	EPSW	R2, R0	exptract psw
000026C8	5020 8EE8		000010E8	2355+	ST	R2, CCPSW	to save CC
000026CC	07FB			2356+	BR	R11	return
000026D0				2357+RE62	DC	0F	
000026D0				2358+	DROP	R5	
000026D0	00000000 00009223			2359	DC	XL16' 00000000000009223372036854775807F'	V1 source
000026D8	37203685 4775807F						
000026E0	7FFFFFFF FFFFFFFF			2360	DC	XL08' 7FFFFFFF FFFFFFFF'	R1 result
				2361			
				2362	VRR_K	VCVDG, 159, 3, 0	LONG_MIN
000026E8				2363+	DS	0FD	
000026E8		000026E8		2364+	USING	*, R5	base for test data and test routine
000026E8	00002704			2365+T63	DC	A(X63)	address of test routine
000026EC	003F			2366+	DC	H' 63'	test number
000026EE	00			2367+	DC	XL1' 00'	
000026EF	9F			2368+	DC	HL1' 159'	i3
000026F0	03			2369+	DC	HL1' 3'	m4
000026F1	00			2370+	DC	HL1' 0'	cc
000026F2	07			2371+	DC	HL1' 7'	cc failed mask
000026F3	E5C3E5C4 C7404040			2372+	DC	CL8' VCVDG'	instruction name
000026FC	00000010			2373+	DC	A(16)	result length
00002700	00002728			2374+REA63	DC	A(RE63)	result address
				2375+*			INSTRUCTION UNDER TEST ROUTINE
00002704				2376+X63	DS	0F	
00002704	E710 8F48 0006		00001148	2377+	VL	V1, V1FUDGE	pollute V1
0000270A	E320 5050 0004		00002738	2378+	LG	R2, RE63+16	get R2 source
00002710	E612 0039 F05A			2379+	VCVDG	V1, R2, 159, 3	test instruction
00002716	E710 8F10 000E		00001110	2380+	VST	V1, V10UTPUT	save
0000271C	B98D 0020			2381+	EPSW	R2, R0	exptract psw
00002720	5020 8EE8		000010E8	2382+	ST	R2, CCPSW	to save CC
00002724	07FB			2383+	BR	R11	return
00002728				2384+RE63	DC	0F	
00002728				2385+	DROP	R5	
00002728	00000000 00009223			2386	DC	XL16' 00000000000009223372036854775808F'	V1 source
00002730	37203685 4775808F						
00002738	80000000 00000000			2387	DC	XL08' 8000000000000000'	R1 result
				2388			
				2389	VRR_K	VCVDG, 159, 3, 0	ULONG_MAX
00002740				2390+	DS	0FD	
00002740		00002740		2391+	USING	*, R5	base for test data and test routine
00002740	0000275C			2392+T64	DC	A(X64)	address of test routine
00002744	0040			2393+	DC	H' 64'	test number
00002746	00			2394+	DC	XL1' 00'	
00002747	9F			2395+	DC	HL1' 159'	i3

LOC	OBJECT	CODE	ADDR1	ADDR2	STMT		
00002748	03				2396+	DC	HL1' 3'
00002749	00				2397+	DC	HL1' 0'
0000274A	07				2398+	DC	HL1' 7'
0000274B	E5C3E5C4	C7404040			2399+	DC	CL8' VCVDG'
00002754	00000010				2400+	DC	A(16)
00002758	00002780				2401+REA64	DC	A(RE64)
					2402+*		
0000275C					2403+X64	DS	OF
0000275C	E710	8F48	0006	00001148	2404+	VL	V1, V1FUDGE
00002762	E320	5050	0004	00002790	2405+	LG	R2, RE64+16
00002768	E612	0039	F05A		2406+	VCVDG	V1, R2, 159, 3
0000276E	E710	8F10	000E	00001110	2407+	VST	V1, V10UTPUT
00002774	B98D	0020			2408+	EPSW	R2, R0
00002778	5020	8EE8		000010E8	2409+	ST	R2, CCPSW
0000277C	07FB				2410+	BR	R11
00002780					2411+RE64	DC	OF
00002780					2412+	DROP	R5
00002780	00000000	00000000			2413	DC	XL16' 00000000000000000000000000000001F'
00002788	00000000	0000001F					
00002790	FFFFFFFF	FFFFFFFF			2414	DC	XL08' FFFFFFFFFFFFFFFFFF'
					2415		
					2416 * VCVDG		m4= 3 (LB=0, P1=1 , CS=1)
					2417 *		i3= 137 (IOM=1, RDC= 9)
					2418		
					2419	VRR_K	VCVDG, 137, 3, 0
00002798					2420+	DS	OFD
00002798			00002798		2421+	USING	*, R5
00002798	000027B4				2422+T65	DC	A(X65)
0000279C	0041				2423+	DC	H' 65'
0000279E	00				2424+	DC	XL1' 00'
0000279F	89				2425+	DC	HL1' 137'
000027A0	03				2426+	DC	HL1' 3'
000027A1	00				2427+	DC	HL1' 0'
000027A2	07				2428+	DC	HL1' 7'
000027A3	E5C3E5C4	C7404040			2429+	DC	CL8' VCVDG'
000027AC	00000010				2430+	DC	A(16)
000027B0	000027D8				2431+REA65	DC	A(RE65)
					2432+*		
000027B4					2433+X65	DS	OF
000027B4	E710	8F48	0006	00001148	2434+	VL	V1, V1FUDGE
000027BA	E320	5050	0004	000027E8	2435+	LG	R2, RE65+16
000027C0	E612	0038	905A		2436+	VCVDG	V1, R2, 137, 3
000027C6	E710	8F10	000E	00001110	2437+	VST	V1, V10UTPUT
000027CC	B98D	0020			2438+	EPSW	R2, R0
000027D0	5020	8EE8		000010E8	2439+	ST	R2, CCPSW
000027D4	07FB				2440+	BR	R11
000027D8					2441+RE65	DC	OF
000027D8					2442+	DROP	R5
000027D8	00000000	00000000			2443	DC	XL16' 00000000000000000000000000000000F'
000027E0	00000000	0000000F					
000027E8	00000000	00000000			2444	DC	FD' 0'
					2445		
					2446	VRR_K	VCVDG, 137, 3, 0
000027F0					2447+	DS	OFD
000027F0			000027F0		2448+	USING	*, R5
000027F0	0000280C				2449+T66	DC	A(X66)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002954	0046			2558+	DC	H' 70'	test number
00002956	00			2559+	DC	XL1' 00'	
00002957	89			2560+	DC	HL1' 137'	i3
00002958	03			2561+	DC	HL1' 3'	m4
00002959	03			2562+	DC	HL1' 3'	cc
0000295A	0E			2563+	DC	HL1' 14'	cc failed mask
0000295B	E5C3E5C4 C7404040			2564+	DC	CL8' VCVDG'	instruction name
00002964	00000010			2565+	DC	A(16)	result length
00002968	00002990			2566+REA70	DC	A(RE70)	result address
				2567+*			INSTRUCTION UNDER TEST ROUTINE
0000296C				2568+X70	DS	0F	
0000296C	E710 8F48 0006		00001148	2569+	VL	V1, V1FUDGE	pollute V1
00002972	E320 5050 0004		000029A0	2570+	LG	R2, RE70+16	get R2 source
00002978	E612 0038 905A			2571+	VCVDG	V1, R2, 137, 3	test instruction
0000297E	E710 8F10 000E		00001110	2572+	VST	V1, V10UTPUT	save
00002984	B98D 0020			2573+	EPSW	R2, R0	exptract psw
00002988	5020 8EE8		000010E8	2574+	ST	R2, CCPSW	to save CC
0000298C	07FB			2575+	BR	R11	return
00002990				2576+RE70	DC	0F	
00002990				2577+	DROP	R5	
00002990	00000000 00000000			2578	DC	XL16' 000000000000000000000000854775807F'	V1 source
00002998	00000085 4775807F						
000029A0	7FFFFFFF FFFFFFFF			2579	DC	XL08' 7FFFFFFF	R1 result
				2580			
				2581	VRR_K	VCVDG, 137, 3, 3	LONG_MIN
000029A8				2582+	DS	0FD	
000029A8		000029A8		2583+	USING	*, R5	base for test data and test routine
000029A8	000029C4			2584+T71	DC	A(X71)	address of test routine
000029AC	0047			2585+	DC	H' 71'	test number
000029AE	00			2586+	DC	XL1' 00'	
000029AF	89			2587+	DC	HL1' 137'	i3
000029B0	03			2588+	DC	HL1' 3'	m4
000029B1	03			2589+	DC	HL1' 3'	cc
000029B2	0E			2590+	DC	HL1' 14'	cc failed mask
000029B3	E5C3E5C4 C7404040			2591+	DC	CL8' VCVDG'	instruction name
000029BC	00000010			2592+	DC	A(16)	result length
000029C0	000029E8			2593+REA71	DC	A(RE71)	result address
				2594+*			INSTRUCTION UNDER TEST ROUTINE
000029C4				2595+X71	DS	0F	
000029C4	E710 8F48 0006		00001148	2596+	VL	V1, V1FUDGE	pollute V1
000029CA	E320 5050 0004		000029F8	2597+	LG	R2, RE71+16	get R2 source
000029D0	E612 0038 905A			2598+	VCVDG	V1, R2, 137, 3	test instruction
000029D6	E710 8F10 000E		00001110	2599+	VST	V1, V10UTPUT	save
000029DC	B98D 0020			2600+	EPSW	R2, R0	exptract psw
000029E0	5020 8EE8		000010E8	2601+	ST	R2, CCPSW	to save CC
000029E4	07FB			2602+	BR	R11	return
000029E8				2603+RE71	DC	0F	
000029E8				2604+	DROP	R5	
000029E8	00000000 00000000			2605	DC	XL16' 000000000000000000000000854775808F'	V1 source
000029F0	00000085 4775808F						
000029F8	80000000 00000000			2606	DC	XL08' 8000000000000000	R1 result
				2607			
				2608	VRR_K	VCVDG, 137, 3, 0	ULONG_MAX
00002A00				2609+	DS	0FD	
00002A00		00002A00		2610+	USING	*, R5	base for test data and test routine
00002A00	00002A1C			2611+T72	DC	A(X72)	address of test routine

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002B60				2720	VRR_K	VCVDG, 159, 9, 0	INT_MAX
00002B60				2721+	DS	OFD	
00002B60		00002B60		2722+	USING	*, R5	base for test data and test routine
00002B60	00002B7C			2723+T76	DC	A(X76)	address of test routine
00002B64	004C			2724+	DC	H' 76'	test number
00002B66	00			2725+	DC	XL1' 00'	
00002B67	9F			2726+	DC	HL1' 159'	i3
00002B68	09			2727+	DC	HL1' 9'	m4
00002B69	00			2728+	DC	HL1' 0'	cc
00002B6A	07			2729+	DC	HL1' 7'	cc failed mask
00002B6B	E5C3E5C4 C7404040			2730+	DC	CL8' VCVDG'	instruction name
00002B74	00000010			2731+	DC	A(16)	result length
00002B78	00002BA0			2732+REA76	DC	A(RE76)	result address
				2733+*			INSTRUCTION UNDER TEST ROUTINE
00002B7C				2734+X76	DS	OF	
00002B7C	E710 8F48 0006		00001148	2735+	VL	V1, V1FUDGE	pollute V1
00002B82	E320 5050 0004		00002BB0	2736+	LG	R2, RE76+16	get R2 source
00002B88	E612 0099 F05A			2737+	VCVDG	V1, R2, 159, 9	test instruction
00002B8E	E710 8F10 000E		00001110	2738+	VST	V1, V10UTPUT	save
00002B94	B98D 0020			2739+	EPSW	R2, R0	exptract psw
00002B98	5020 8EE8		000010E8	2740+	ST	R2, CCPSW	to save CC
00002B9C	07FB			2741+	BR	R11	return
00002BA0				2742+RE76	DC	OF	
00002BA0				2743+	DROP	R5	
00002BA0	00000000 00000000			2744	DC	XL16' 00000000000000000000000002147483647C'	V1 result
00002BA8	00000214 7483647C						
00002BB0	00000000 7FFFFFFF			2745	DC	FD' 2147483647'	R2 source
				2746			
				2747	VRR_K	VCVDG, 159, 9, 0	INT_MIN
00002BB8				2748+	DS	OFD	
00002BB8		00002BB8		2749+	USING	*, R5	base for test data and test routine
00002BB8	00002BD4			2750+T77	DC	A(X77)	address of test routine
00002BBC	004D			2751+	DC	H' 77'	test number
00002BBE	00			2752+	DC	XL1' 00'	
00002BBF	9F			2753+	DC	HL1' 159'	i3
00002BC0	09			2754+	DC	HL1' 9'	m4
00002BC1	00			2755+	DC	HL1' 0'	cc
00002BC2	07			2756+	DC	HL1' 7'	cc failed mask
00002BC3	E5C3E5C4 C7404040			2757+	DC	CL8' VCVDG'	instruction name
00002BCC	00000010			2758+	DC	A(16)	result length
00002BD0	00002BF8			2759+REA77	DC	A(RE77)	result address
				2760+*			INSTRUCTION UNDER TEST ROUTINE
00002BD4				2761+X77	DS	OF	
00002BD4	E710 8F48 0006		00001148	2762+	VL	V1, V1FUDGE	pollute V1
00002BDA	E320 5050 0004		00002C08	2763+	LG	R2, RE77+16	get R2 source
00002BE0	E612 0099 F05A			2764+	VCVDG	V1, R2, 159, 9	test instruction
00002BE6	E710 8F10 000E		00001110	2765+	VST	V1, V10UTPUT	save
00002BEC	B98D 0020			2766+	EPSW	R2, R0	exptract psw
00002BF0	5020 8EE8		000010E8	2767+	ST	R2, CCPSW	to save CC
00002BF4	07FB			2768+	BR	R11	return
00002BF8				2769+RE77	DC	OF	
00002BF8				2770+	DROP	R5	
00002BF8	00000000 00018446			2771	DC	XL16' 00000000000018446744071562067968C'	V1 result
00002C00	74407156 2067968C						
00002C08	FFFFFFFF 80000000			2772	DC	XL8' FFFFFFFF80000000'	R2 source
				2773 *	DC	FD' - 2147483648'	R2 sourc

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2774		
				2775	VRR_K VCVDG, 159, 9, 0	LONG_MAX
00002C10				2776+	DS OFD	
00002C10		00002C10		2777+	USING *, R5	base for test data and test routine
00002C10	00002C2C			2778+T78	DC A(X78)	address of test routine
00002C14	004E			2779+	DC H' 78'	test number
00002C16	00			2780+	DC XL1' 00'	
00002C17	9F			2781+	DC HL1' 159'	i3
00002C18	09			2782+	DC HL1' 9'	m4
00002C19	00			2783+	DC HL1' 0'	cc
00002C1A	07			2784+	DC HL1' 7'	cc failed mask
00002C1B	E5C3E5C4 C7404040			2785+	DC CL8' VCVDG'	instruction name
00002C24	00000010			2786+	DC A(16)	result length
00002C28	00002C50			2787+REA78	DC A(RE78)	result address
				2788+*		INSTRUCTION UNDER TEST ROUTINE
00002C2C				2789+X78	DS OF	
00002C2C	E710 8F48 0006		00001148	2790+	VL V1, V1FUDGE	pollute V1
00002C32	E320 5050 0004		00002C60	2791+	LG R2, RE78+16	get R2 source
00002C38	E612 0099 F05A			2792+	VCVDG V1, R2, 159, 9	test instruction
00002C3E	E710 8F10 000E		00001110	2793+	VST V1, V10UTPUT	save
00002C44	B98D 0020			2794+	EPSW R2, R0	exptract psw
00002C48	5020 8EE8		000010E8	2795+	ST R2, CCPSW	to save CC
00002C4C	07FB			2796+	BR R11	return
00002C50				2797+RE78	DC OF	
00002C50				2798+	DROP R5	
00002C50	00000000 00009223			2799	DC XL16' 00000000000009223372036854775807C'	V1 source
00002C58	37203685 4775807C					
00002C60	7FFFFFFF FFFFFFFF			2800	DC XL08' 7FFFFFFF'	R1 result
				2801		
				2802	VRR_K VCVDG, 159, 9, 0	LONG_MIN
00002C68				2803+	DS OFD	
00002C68		00002C68		2804+	USING *, R5	base for test data and test routine
00002C68	00002C84			2805+T79	DC A(X79)	address of test routine
00002C6C	004F			2806+	DC H' 79'	test number
00002C6E	00			2807+	DC XL1' 00'	
00002C6F	9F			2808+	DC HL1' 159'	i3
00002C70	09			2809+	DC HL1' 9'	m4
00002C71	00			2810+	DC HL1' 0'	cc
00002C72	07			2811+	DC HL1' 7'	cc failed mask
00002C73	E5C3E5C4 C7404040			2812+	DC CL8' VCVDG'	instruction name
00002C7C	00000010			2813+	DC A(16)	result length
00002C80	00002CA8			2814+REA79	DC A(RE79)	result address
				2815+*		INSTRUCTION UNDER TEST ROUTINE
00002C84				2816+X79	DS OF	
00002C84	E710 8F48 0006		00001148	2817+	VL V1, V1FUDGE	pollute V1
00002C8A	E320 5050 0004		00002CB8	2818+	LG R2, RE79+16	get R2 source
00002C90	E612 0099 F05A			2819+	VCVDG V1, R2, 159, 9	test instruction
00002C96	E710 8F10 000E		00001110	2820+	VST V1, V10UTPUT	save
00002C9C	B98D 0020			2821+	EPSW R2, R0	exptract psw
00002CA0	5020 8EE8		000010E8	2822+	ST R2, CCPSW	to save CC
00002CA4	07FB			2823+	BR R11	return
00002CA8				2824+RE79	DC OF	
00002CA8				2825+	DROP R5	
00002CA8	00000000 00009223			2826	DC XL16' 00000000000009223372036854775808C'	V1 source
00002CB0	37203685 4775808C					
00002CB8	80000000 00000000			2827	DC XL08' 8000000000000000'	R1 result

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2828		
				2829	VRR_K VCVDG, 159, 9, 0	ULONG_MAX
00002CC0				2830+	DS OFD	
00002CC0		00002CC0		2831+	USING *, R5	base for test data and test routine
00002CC0	00002CDC			2832+T80	DC A(X80)	address of test routine
00002CC4	0050			2833+	DC H' 80'	test number
00002CC6	00			2834+	DC XL1' 00'	
00002CC7	9F			2835+	DC HL1' 159'	i3
00002CC8	09			2836+	DC HL1' 9'	m4
00002CC9	00			2837+	DC HL1' 0'	cc
00002CCA	07			2838+	DC HL1' 7'	cc failed mask
00002CCB	E5C3E5C4 C7404040			2839+	DC CL8' VCVDG'	instruction name
00002CD4	00000010			2840+	DC A(16)	result length
00002CD8	00002D00			2841+REA80	DC A(RE80)	result address
				2842+*		INSTRUCTION UNDER TEST ROUTINE
00002CDC				2843+X80	DS OF	
00002CDC	E710 8F48 0006		00001148	2844+	VL V1, V1FUDGE	pollute V1
00002CE2	E320 5050 0004		00002D10	2845+	LG R2, RE80+16	get R2 source
00002CE8	E612 0099 F05A			2846+	VCVDG V1, R2, 159, 9	test instruction
00002CEE	E710 8F10 000E		00001110	2847+	VST V1, V10UTPUT	save
00002CF4	B98D 0020			2848+	EPSW R2, R0	exptract psw
00002CF8	5020 8EE8		000010E8	2849+	ST R2, CCPSW	to save CC
00002CFC	07FB			2850+	BR R11	return
00002D00				2851+RE80	DC OF	
00002D00				2852+	DROP R5	
00002D00	00000000 00018446			2853	DC XL16' 00000000000018446744073709551615C'	V1 source
00002D08	74407370 9551615C					
00002D10	FFFFFFFF FFFFFFFF			2854	DC XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				2855		
				2856 * VCVDG	m4= 9 (LB=1, P1=0 , CS=1)	
				2857 *	i3= 137 (IOM=1, RDC= 9)	
				2858		
				2859	VRR_K VCVDG, 137, 9, 0	
00002D18				2860+	DS OFD	
00002D18		00002D18		2861+	USING *, R5	base for test data and test routine
00002D18	00002D34			2862+T81	DC A(X81)	address of test routine
00002D1C	0051			2863+	DC H' 81'	test number
00002D1E	00			2864+	DC XL1' 00'	
00002D1F	89			2865+	DC HL1' 137'	i3
00002D20	09			2866+	DC HL1' 9'	m4
00002D21	00			2867+	DC HL1' 0'	cc
00002D22	07			2868+	DC HL1' 7'	cc failed mask
00002D23	E5C3E5C4 C7404040			2869+	DC CL8' VCVDG'	instruction name
00002D2C	00000010			2870+	DC A(16)	result length
00002D30	00002D58			2871+REA81	DC A(RE81)	result address
				2872+*		INSTRUCTION UNDER TEST ROUTINE
00002D34				2873+X81	DS OF	
00002D34	E710 8F48 0006		00001148	2874+	VL V1, V1FUDGE	pollute V1
00002D3A	E320 5050 0004		00002D68	2875+	LG R2, RE81+16	get R2 source
00002D40	E612 0098 905A			2876+	VCVDG V1, R2, 137, 9	test instruction
00002D46	E710 8F10 000E		00001110	2877+	VST V1, V10UTPUT	save
00002D4C	B98D 0020			2878+	EPSW R2, R0	exptract psw
00002D50	5020 8EE8		000010E8	2879+	ST R2, CCPSW	to save CC
00002D54	07FB			2880+	BR R11	return
00002D58				2881+RE81	DC OF	
00002D58				2882+	DROP R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002D58	00000000 00000000			2883	DC	XL16' 00000000000000000000000000000000C'	V1 result
00002D60	00000000 0000000C						
00002D68	00000000 00000000			2884	DC	FD' 0'	R2 source
				2885			
				2886	VRR_K	VCVDG, 137, 9, 0	
00002D70				2887+	DS	OFD	
00002D70		00002D70		2888+	USING	*, R5	base for test data and test routine
00002D70	00002D8C			2889+T82	DC	A(X82)	address of test routine
00002D74	0052			2890+	DC	H' 82'	test number
00002D76	00			2891+	DC	XL1' 00'	
00002D77	89			2892+	DC	HL1' 137'	i3
00002D78	09			2893+	DC	HL1' 9'	m4
00002D79	00			2894+	DC	HL1' 0'	cc
00002D7A	07			2895+	DC	HL1' 7'	cc failed mask
00002D7B	E5C3E5C4 C7404040			2896+	DC	CL8' VCVDG'	instruction name
00002D84	00000010			2897+	DC	A(16)	result length
00002D88	00002DB0			2898+REA82	DC	A(RE82)	result address
				2899+*			INSTRUCTION UNDER TEST ROUTINE
00002D8C				2900+X82	DS	OF	
00002D8C	E710 8F48 0006		00001148	2901+	VL	V1, V1FUDGE	pollute V1
00002D92	E320 5050 0004		00002DC0	2902+	LG	R2, RE82+16	get R2 source
00002D98	E612 0098 905A			2903+	VCVDG	V1, R2, 137, 9	test instruction
00002D9E	E710 8F10 000E		00001110	2904+	VST	V1, V10UTPUT	save
00002DA4	B98D 0020			2905+	EPSW	R2, R0	exptract psw
00002DA8	5020 8EE8		000010E8	2906+	ST	R2, CCPSW	to save CC
00002DAC	07FB			2907+	BR	R11	return
00002DB0				2908+RE82	DC	OF	
00002DB0				2909+	DROP	R5	
00002DB0	00000000 00000000			2910	DC	XL16' 000000000000000000000000000000001C'	V1 result
00002DB8	00000000 0000001C						
00002DC0	00000000 00000001			2911	DC	FD' 1'	R2 source
				2912			
				2913	VRR_K	VCVDG, 137, 9, 3	UINT_MAX
00002DC8				2914+	DS	OFD	
00002DC8		00002DC8		2915+	USING	*, R5	base for test data and test routine
00002DC8	00002DE4			2916+T83	DC	A(X83)	address of test routine
00002DCC	0053			2917+	DC	H' 83'	test number
00002DCE	00			2918+	DC	XL1' 00'	
00002DCF	89			2919+	DC	HL1' 137'	i3
00002DD0	09			2920+	DC	HL1' 9'	m4
00002DD1	03			2921+	DC	HL1' 3'	cc
00002DD2	0E			2922+	DC	HL1' 14'	cc failed mask
00002DD3	E5C3E5C4 C7404040			2923+	DC	CL8' VCVDG'	instruction name
00002DDC	00000010			2924+	DC	A(16)	result length
00002DE0	00002E08			2925+REA83	DC	A(RE83)	result address
				2926+*			INSTRUCTION UNDER TEST ROUTINE
00002DE4				2927+X83	DS	OF	
00002DE4	E710 8F48 0006		00001148	2928+	VL	V1, V1FUDGE	pollute V1
00002DEA	E320 5050 0004		00002E18	2929+	LG	R2, RE83+16	get R2 source
00002DF0	E612 0098 905A			2930+	VCVDG	V1, R2, 137, 9	test instruction
00002DF6	E710 8F10 000E		00001110	2931+	VST	V1, V10UTPUT	save
00002DFC	B98D 0020			2932+	EPSW	R2, R0	exptract psw
00002E00	5020 8EE8		000010E8	2933+	ST	R2, CCPSW	to save CC
00002E04	07FB			2934+	BR	R11	return
00002E08				2935+RE83	DC	OF	
00002E08				2936+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002E08	00000000 00000000			2937	DC	XL16' 000000000000000000000000709551615C'	V1 source
00002E10	00000070 9551615C						
00002E18	FFFFFFFF FFFFFFFF			2938	DC	FD' - 1'	R2 source
				2939			
				2940	VRR_K	VCVDG, 137, 9, 3	INT_MAX
00002E20				2941+	DS	OFD	
00002E20		00002E20		2942+	USING	*, R5	base for test data and test routine
00002E20	00002E3C			2943+T84	DC	A(X84)	address of test routine
00002E24	0054			2944+	DC	H' 84'	test number
00002E26	00			2945+	DC	XL1' 00'	
00002E27	89			2946+	DC	HL1' 137'	i3
00002E28	09			2947+	DC	HL1' 9'	m4
00002E29	03			2948+	DC	HL1' 3'	cc
00002E2A	0E			2949+	DC	HL1' 14'	cc failed mask
00002E2B	E5C3E5C4 C7404040			2950+	DC	CL8' VCVDG'	instruction name
00002E34	00000010			2951+	DC	A(16)	result length
00002E38	00002E60			2952+REA84	DC	A(RE84)	result address
				2953+*			INSTRUCTION UNDER TEST ROUTINE
00002E3C				2954+X84	DS	OF	
00002E3C	E710 8F48 0006		00001148	2955+	VL	V1, V1FUDGE	pollute V1
00002E42	E320 5050 0004		00002E70	2956+	LG	R2, RE84+16	get R2 source
00002E48	E612 0098 905A			2957+	VCVDG	V1, R2, 137, 9	test instruction
00002E4E	E710 8F10 000E		00001110	2958+	VST	V1, V10UTPUT	save
00002E54	B98D 0020			2959+	EPSW	R2, R0	exptract psw
00002E58	5020 8EE8		000010E8	2960+	ST	R2, CCPSW	to save CC
00002E5C	07FB			2961+	BR	R11	return
00002E60				2962+RE84	DC	OF	
00002E60				2963+	DROP	R5	
00002E60	00000000 00000000			2964	DC	XL16' 000000000000000000000000147483647C'	V1 result
00002E68	00000014 7483647C						
00002E70	00000000 7FFFFFFF			2965	DC	FD' 2147483647'	R2 source
				2966			
				2967	VRR_K	VCVDG, 137, 9, 3	INT_MIN
00002E78				2968+	DS	OFD	
00002E78		00002E78		2969+	USING	*, R5	base for test data and test routine
00002E78	00002E94			2970+T85	DC	A(X85)	address of test routine
00002E7C	0055			2971+	DC	H' 85'	test number
00002E7E	00			2972+	DC	XL1' 00'	
00002E7F	89			2973+	DC	HL1' 137'	i3
00002E80	09			2974+	DC	HL1' 9'	m4
00002E81	03			2975+	DC	HL1' 3'	cc
00002E82	0E			2976+	DC	HL1' 14'	cc failed mask
00002E83	E5C3E5C4 C7404040			2977+	DC	CL8' VCVDG'	instruction name
00002E8C	00000010			2978+	DC	A(16)	result length
00002E90	00002EB8			2979+REA85	DC	A(RE85)	result address
				2980+*			INSTRUCTION UNDER TEST ROUTINE
00002E94				2981+X85	DS	OF	
00002E94	E710 8F48 0006		00001148	2982+	VL	V1, V1FUDGE	pollute V1
00002E9A	E320 5050 0004		00002EC8	2983+	LG	R2, RE85+16	get R2 source
00002EA0	E612 0098 905A			2984+	VCVDG	V1, R2, 137, 9	test instruction
00002EA6	E710 8F10 000E		00001110	2985+	VST	V1, V10UTPUT	save
00002EAC	B98D 0020			2986+	EPSW	R2, R0	exptract psw
00002EB0	5020 8EE8		000010E8	2987+	ST	R2, CCPSW	to save CC
00002EB4	07FB			2988+	BR	R11	return
00002EB8				2989+RE85	DC	OF	
00002EB8				2990+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002EB8	00000000 00000000			2991	DC	XL16' 000000000000000000000000562067968C'	V1 result
00002EC0	00000056 2067968C						
00002EC8	FFFFFFFF 80000000			2992	DC	FD' - 2147483648'	
				2993			
				2994	VRR_K	VCVDG, 137, 9, 3	LONG_MAX
00002ED0				2995+	DS	OFD	
00002ED0		00002ED0		2996+	USING	*, R5	base for test data and test routine
00002ED0	00002EEC			2997+T86	DC	A(X86)	address of test routine
00002ED4	0056			2998+	DC	H' 86'	test number
00002ED6	00			2999+	DC	XL1' 00'	
00002ED7	89			3000+	DC	HL1' 137'	i3
00002ED8	09			3001+	DC	HL1' 9'	m4
00002ED9	03			3002+	DC	HL1' 3'	cc
00002EDA	0E			3003+	DC	HL1' 14'	cc failed mask
00002EDB	E5C3E5C4 C7404040			3004+	DC	CL8' VCVDG'	instruction name
00002EE4	00000010			3005+	DC	A(16)	result length
00002EE8	00002F10			3006+REA86	DC	A(RE86)	result address
				3007+*			INSTRUCTION UNDER TEST ROUTINE
00002EEC				3008+X86	DS	OF	
00002EEC	E710 8F48 0006		00001148	3009+	VL	V1, V1FUDGE	pollute V1
00002EF2	E320 5050 0004		00002F20	3010+	LG	R2, RE86+16	get R2 source
00002EF8	E612 0098 905A			3011+	VCVDG	V1, R2, 137, 9	test instruction
00002EFE	E710 8F10 000E		00001110	3012+	VST	V1, V10UTPUT	save
00002F04	B98D 0020			3013+	EPSW	R2, R0	exptract psw
00002F08	5020 8EE8		000010E8	3014+	ST	R2, CCPSW	to save CC
00002F0C	07FB			3015+	BR	R11	return
00002F10				3016+RE86	DC	OF	
00002F10				3017+	DROP	R5	
00002F10	00000000 00000000			3018	DC	XL16' 000000000000000000000000854775807C'	V1 source
00002F18	00000085 4775807C						
00002F20	7FFFFFFFF FFFFFFFF			3019	DC	XL08' 7FFFFFFFFFFFFFFFFF'	R1 result
				3020			
				3021	VRR_K	VCVDG, 137, 9, 3	LONG_MIN
00002F28				3022+	DS	OFD	
00002F28		00002F28		3023+	USING	*, R5	base for test data and test routine
00002F28	00002F44			3024+T87	DC	A(X87)	address of test routine
00002F2C	0057			3025+	DC	H' 87'	test number
00002F2E	00			3026+	DC	XL1' 00'	
00002F2F	89			3027+	DC	HL1' 137'	i3
00002F30	09			3028+	DC	HL1' 9'	m4
00002F31	03			3029+	DC	HL1' 3'	cc
00002F32	0E			3030+	DC	HL1' 14'	cc failed mask
00002F33	E5C3E5C4 C7404040			3031+	DC	CL8' VCVDG'	instruction name
00002F3C	00000010			3032+	DC	A(16)	result length
00002F40	00002F68			3033+REA87	DC	A(RE87)	result address
				3034+*			INSTRUCTION UNDER TEST ROUTINE
00002F44				3035+X87	DS	OF	
00002F44	E710 8F48 0006		00001148	3036+	VL	V1, V1FUDGE	pollute V1
00002F4A	E320 5050 0004		00002F78	3037+	LG	R2, RE87+16	get R2 source
00002F50	E612 0098 905A			3038+	VCVDG	V1, R2, 137, 9	test instruction
00002F56	E710 8F10 000E		00001110	3039+	VST	V1, V10UTPUT	save
00002F5C	B98D 0020			3040+	EPSW	R2, R0	exptract psw
00002F60	5020 8EE8		000010E8	3041+	ST	R2, CCPSW	to save CC
00002F64	07FB			3042+	BR	R11	return
00002F68				3043+RE87	DC	OF	
00002F68				3044+	DROP	R5	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002F68	00000000 00000000			3045	DC	XL16' 0000000000000000000000000854775808C'	V1 source
00002F70	00000085 4775808C						
00002F78	80000000 00000000			3046	DC	XL08' 800000000000000000'	R1 result
				3047			
				3048	VRR_K	VCVDG, 137, 9, 3	ULONG_MAX
00002F80				3049+	DS	OFD	
00002F80		00002F80		3050+	USING	*, R5	base for test data and test routine
00002F80	00002F9C			3051+T88	DC	A(X88)	address of test routine
00002F84	0058			3052+	DC	H' 88'	test number
00002F86	00			3053+	DC	XL1' 00'	
00002F87	89			3054+	DC	HL1' 137'	i3
00002F88	09			3055+	DC	HL1' 9'	m4
00002F89	03			3056+	DC	HL1' 3'	cc
00002F8A	0E			3057+	DC	HL1' 14'	cc failed mask
00002F8B	E5C3E5C4 C7404040			3058+	DC	CL8' VCVDG'	instruction name
00002F94	00000010			3059+	DC	A(16)	result length
00002F98	00002FC0			3060+REA88	DC	A(RE88)	result address
				3061+*			INSTRUCTION UNDER TEST ROUTINE
00002F9C				3062+X88	DS	OF	
00002F9C	E710 8F48 0006		00001148	3063+	VL	V1, V1FUDGE	pollute V1
00002FA2	E320 5050 0004		00002FD0	3064+	LG	R2, RE88+16	get R2 source
00002FA8	E612 0098 905A			3065+	VCVDG	V1, R2, 137, 9	test instruction
00002FAE	E710 8F10 000E		00001110	3066+	VST	V1, V10UTPUT	save
00002FB4	B98D 0020			3067+	EPSW	R2, R0	exptract psw
00002FB8	5020 8EE8		000010E8	3068+	ST	R2, CCPSW	to save CC
00002FBC	07FB			3069+	BR	R11	return
00002FC0				3070+RE88	DC	OF	
00002FC0				3071+	DROP	R5	
00002FC0	00000000 00000000			3072	DC	XL16' 000000000000000000000000709551615C'	V1 source
00002FC8	00000070 9551615C						
00002FD0	FFFFFFFF FFFFFFFF			3073	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				3074			
				3075 *			
				3076 * VCVDG		m4= 11 (LB=1, P1=1 , CS=1)	
				3077 *		i3= 159 (IOM=1, RDC=31)	
				3078			
				3079	VRR_K	VCVDG, 159, 11, 0	
00002FD8				3080+	DS	OFD	
00002FD8		00002FD8		3081+	USING	*, R5	base for test data and test routine
00002FD8	00002FF4			3082+T89	DC	A(X89)	address of test routine
00002FDC	0059			3083+	DC	H' 89'	test number
00002FDE	00			3084+	DC	XL1' 00'	
00002FDF	9F			3085+	DC	HL1' 159'	i3
00002FE0	0B			3086+	DC	HL1' 11'	m4
00002FE1	00			3087+	DC	HL1' 0'	cc
00002FE2	07			3088+	DC	HL1' 7'	cc failed mask
00002FE3	E5C3E5C4 C7404040			3089+	DC	CL8' VCVDG'	instruction name
00002FEC	00000010			3090+	DC	A(16)	result length
00002FF0	00003018			3091+REA89	DC	A(RE89)	result address
				3092+*			INSTRUCTION UNDER TEST ROUTINE
00002FF4				3093+X89	DS	OF	
00002FF4	E710 8F48 0006		00001148	3094+	VL	V1, V1FUDGE	pollute V1
00002FFA	E320 5050 0004		00003028	3095+	LG	R2, RE89+16	get R2 source
00003000	E612 00B9 F05A			3096+	VCVDG	V1, R2, 159, 11	test instruction
00003006	E710 8F10 000E		00001110	3097+	VST	V1, V10UTPUT	save
0000300C	B98D 0020			3098+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003010	5020 8EE8		000010E8	3099+	ST	R2, CCPSW	to save CC
00003014	07FB			3100+	BR	R11	return
00003018				3101+RE89	DC	0F	
00003018				3102+	DROP	R5	
00003018	00000000 00000000			3103	DC	XL16' 000000000000000000000000000000F'	V1 result
00003020	00000000 0000000F						
00003028	00000000 00000000			3104	DC	FD' 0'	R2 source
				3105			
				3106	VRR_K	VCVDG, 159, 11, 0	
00003030				3107+	DS	0FD	
00003030		00003030		3108+	USING	*, R5	base for test data and test routine
00003030	0000304C			3109+T90	DC	A(X90)	address of test routine
00003034	005A			3110+	DC	H' 90'	test number
00003036	00			3111+	DC	XL1' 00'	
00003037	9F			3112+	DC	HL1' 159'	i3
00003038	0B			3113+	DC	HL1' 11'	m4
00003039	00			3114+	DC	HL1' 0'	cc
0000303A	07			3115+	DC	HL1' 7'	cc failed mask
0000303B	E5C3E5C4 C7404040			3116+	DC	CL8' VCVDG'	instruction name
00003044	00000010			3117+	DC	A(16)	result length
00003048	00003070			3118+REA90	DC	A(RE90)	result address
				3119+*			INSTRUCTION UNDER TEST ROUTINE
0000304C				3120+X90	DS	0F	
0000304C	E710 8F48 0006		00001148	3121+	VL	V1, V1FUDGE	pollute V1
00003052	E320 5050 0004		00003080	3122+	LG	R2, RE90+16	get R2 source
00003058	E612 00B9 F05A			3123+	VCVDG	V1, R2, 159, 11	test instruction
0000305E	E710 8F10 000E		00001110	3124+	VST	V1, V10UTPUT	save
00003064	B98D 0020			3125+	EPSW	R2, R0	exptract psw
00003068	5020 8EE8		000010E8	3126+	ST	R2, CCPSW	to save CC
0000306C	07FB			3127+	BR	R11	return
00003070				3128+RE90	DC	0F	
00003070				3129+	DROP	R5	
00003070	00000000 00000000			3130	DC	XL16' 000000000000000000000000000001F'	V1 result
00003078	00000000 0000001F						
00003080	00000000 00000001			3131	DC	FD' 1'	R2 source
				3132			
				3133	VRR_K	VCVDG, 159, 11, 0	UINT_MAX
00003088				3134+	DS	0FD	
00003088		00003088		3135+	USING	*, R5	base for test data and test routine
00003088	000030A4			3136+T91	DC	A(X91)	address of test routine
0000308C	005B			3137+	DC	H' 91'	test number
0000308E	00			3138+	DC	XL1' 00'	
0000308F	9F			3139+	DC	HL1' 159'	i3
00003090	0B			3140+	DC	HL1' 11'	m4
00003091	00			3141+	DC	HL1' 0'	cc
00003092	07			3142+	DC	HL1' 7'	cc failed mask
00003093	E5C3E5C4 C7404040			3143+	DC	CL8' VCVDG'	instruction name
0000309C	00000010			3144+	DC	A(16)	result length
000030A0	000030C8			3145+REA91	DC	A(RE91)	result address
				3146+*			INSTRUCTION UNDER TEST ROUTINE
000030A4				3147+X91	DS	0F	
000030A4	E710 8F48 0006		00001148	3148+	VL	V1, V1FUDGE	pollute V1
000030AA	E320 5050 0004		000030D8	3149+	LG	R2, RE91+16	get R2 source
000030B0	E612 00B9 F05A			3150+	VCVDG	V1, R2, 159, 11	test instruction
000030B6	E710 8F10 000E		00001110	3151+	VST	V1, V10UTPUT	save
000030BC	B98D 0020			3152+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000030C0	5020 8EE8		000010E8	3153+	ST	R2, CCPSW	to save CC
000030C4	07FB			3154+	BR	R11	return
000030C8				3155+RE91	DC	0F	
000030C8				3156+	DROP	R5	
000030C8	00000000 00018446			3157	DC	XL16' 00000000000018446744073709551615F'	V1 source
000030D0	74407370 9551615F						
000030D8	FFFFFFFF FFFFFFFF			3158	DC	FD' - 1'	R2 source
				3159			
				3160	VRR_K	VCVDG, 159, 11, 0	INT_MAX
000030E0				3161+	DS	0FD	
000030E0		000030E0		3162+	USING	*, R5	base for test data and test routine
000030E0	000030FC			3163+T92	DC	A(X92)	address of test routine
000030E4	005C			3164+	DC	H' 92'	test number
000030E6	00			3165+	DC	XL1' 00'	
000030E7	9F			3166+	DC	HL1' 159'	i3
000030E8	0B			3167+	DC	HL1' 11'	m4
000030E9	00			3168+	DC	HL1' 0'	cc
000030EA	07			3169+	DC	HL1' 7'	cc failed mask
000030EB	E5C3E5C4 C7404040			3170+	DC	CL8' VCVDG'	instruction name
000030F4	00000010			3171+	DC	A(16)	result length
000030F8	00003120			3172+REA92	DC	A(RE92)	result address
				3173+*			INSTRUCTION UNDER TEST ROUTINE
000030FC				3174+X92	DS	0F	
000030FC	E710 8F48 0006		00001148	3175+	VL	V1, V1FUDGE	pollute V1
00003102	E320 5050 0004		00003130	3176+	LG	R2, RE92+16	get R2 source
00003108	E612 00B9 F05A			3177+	VCVDG	V1, R2, 159, 11	test instruction
0000310E	E710 8F10 000E		00001110	3178+	VST	V1, V10UTPUT	save
00003114	B98D 0020			3179+	EPSW	R2, R0	exptract psw
00003118	5020 8EE8		000010E8	3180+	ST	R2, CCPSW	to save CC
0000311C	07FB			3181+	BR	R11	return
00003120				3182+RE92	DC	0F	
00003120				3183+	DROP	R5	
00003120	00000000 00000000			3184	DC	XL16' 000000000000000000000002147483647F'	V1 result
00003128	00000214 7483647F						
00003130	00000000 7FFFFFFF			3185	DC	FD' 2147483647'	R2 source
				3186			
				3187	VRR_K	VCVDG, 159, 11, 0	INT_MIN
00003138				3188+	DS	0FD	
00003138		00003138		3189+	USING	*, R5	base for test data and test routine
00003138	00003154			3190+T93	DC	A(X93)	address of test routine
0000313C	005D			3191+	DC	H' 93'	test number
0000313E	00			3192+	DC	XL1' 00'	
0000313F	9F			3193+	DC	HL1' 159'	i3
00003140	0B			3194+	DC	HL1' 11'	m4
00003141	00			3195+	DC	HL1' 0'	cc
00003142	07			3196+	DC	HL1' 7'	cc failed mask
00003143	E5C3E5C4 C7404040			3197+	DC	CL8' VCVDG'	instruction name
0000314C	00000010			3198+	DC	A(16)	result length
00003150	00003178			3199+REA93	DC	A(RE93)	result address
				3200+*			INSTRUCTION UNDER TEST ROUTINE
00003154				3201+X93	DS	0F	
00003154	E710 8F48 0006		00001148	3202+	VL	V1, V1FUDGE	pollute V1
0000315A	E320 5050 0004		00003188	3203+	LG	R2, RE93+16	get R2 source
00003160	E612 00B9 F05A			3204+	VCVDG	V1, R2, 159, 11	test instruction
00003166	E710 8F10 000E		00001110	3205+	VST	V1, V10UTPUT	save
0000316C	B98D 0020			3206+	EPSW	R2, R0	exptract psw

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003170	5020 8EE8		000010E8	3207+	ST	R2, CCPSW	to save CC
00003174	07FB			3208+	BR	R11	return
00003178				3209+RE93	DC	0F	
00003178				3210+	DROP	R5	
00003178	00000000 00018446			3211	DC	XL16' 00000000000018446744071562067968F'	V1 result
00003180	74407156 2067968F						
00003188	FFFFFFFF 80000000			3212	DC	XL8' FFFFFFFF80000000'	R2 source
				3213 *	DC	FD' - 2147483648'	R2 source
				3214			
				3215	VRR_K	VCVDG, 159, 11, 0	LONG_MAX
00003190				3216+	DS	0FD	
00003190		00003190		3217+	USING	*, R5	base for test data and test routine
00003190	000031AC			3218+T94	DC	A(X94)	address of test routine
00003194	005E			3219+	DC	H' 94'	test number
00003196	00			3220+	DC	XL1' 00'	
00003197	9F			3221+	DC	HL1' 159'	i3
00003198	0B			3222+	DC	HL1' 11'	m4
00003199	00			3223+	DC	HL1' 0'	cc
0000319A	07			3224+	DC	HL1' 7'	cc failed mask
0000319B	E5C3E5C4 C7404040			3225+	DC	CL8' VCVDG'	instruction name
000031A4	00000010			3226+	DC	A(16)	result length
000031A8	000031D0			3227+REA94	DC	A(RE94)	result address
				3228+*			INSTRUCTION UNDER TEST ROUTINE
000031AC				3229+X94	DS	0F	
000031AC	E710 8F48 0006		00001148	3230+	VL	V1, V1FUDGE	pollute V1
000031B2	E320 5050 0004		000031E0	3231+	LG	R2, RE94+16	get R2 source
000031B8	E612 00B9 F05A			3232+	VCVDG	V1, R2, 159, 11	test instruction
000031BE	E710 8F10 000E		00001110	3233+	VST	V1, V10UTPUT	save
000031C4	B98D 0020			3234+	EPSW	R2, R0	extract psw
000031C8	5020 8EE8		000010E8	3235+	ST	R2, CCPSW	to save CC
000031CC	07FB			3236+	BR	R11	return
000031D0				3237+RE94	DC	0F	
000031D0				3238+	DROP	R5	
000031D0	00000000 00009223			3239	DC	XL16' 00000000000009223372036854775807F'	V1 source
000031D8	37203685 4775807F						
000031E0	7FFFFFFFF FFFFFFFF			3240	DC	XL08' 7FFFFFFFFFFFFFFFFF'	R1 result
				3241			
				3242	VRR_K	VCVDG, 159, 11, 0	LONG_MIN
000031E8				3243+	DS	0FD	
000031E8		000031E8		3244+	USING	*, R5	base for test data and test routine
000031E8	00003204			3245+T95	DC	A(X95)	address of test routine
000031EC	005F			3246+	DC	H' 95'	test number
000031EE	00			3247+	DC	XL1' 00'	
000031EF	9F			3248+	DC	HL1' 159'	i3
000031F0	0B			3249+	DC	HL1' 11'	m4
000031F1	00			3250+	DC	HL1' 0'	cc
000031F2	07			3251+	DC	HL1' 7'	cc failed mask
000031F3	E5C3E5C4 C7404040			3252+	DC	CL8' VCVDG'	instruction name
000031FC	00000010			3253+	DC	A(16)	result length
00003200	00003228			3254+REA95	DC	A(RE95)	result address
				3255+*			INSTRUCTION UNDER TEST ROUTINE
00003204				3256+X95	DS	0F	
00003204	E710 8F48 0006		00001148	3257+	VL	V1, V1FUDGE	pollute V1
0000320A	E320 5050 0004		00003238	3258+	LG	R2, RE95+16	get R2 source
00003210	E612 00B9 F05A			3259+	VCVDG	V1, R2, 159, 11	test instruction
00003216	E710 8F10 000E		00001110	3260+	VST	V1, V10UTPUT	save

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000321C	B98D 0020			3261+	EPSW	R2, R0	exptract psw
00003220	5020 8EE8		000010E8	3262+	ST	R2, CCPSW	to save CC
00003224	07FB			3263+	BR	R11	return
00003228				3264+RE95	DC	0F	
00003228				3265+	DROP	R5	
00003228	00000000 00009223			3266	DC	XL16' 00000000000009223372036854775808F'	V1 source
00003230	37203685 4775808F						
00003238	80000000 00000000			3267	DC	XL08' 8000000000000000'	R1 result
				3268			
				3269	VRR_K	VCVDG, 159, 11, 0	ULONG_MAX
00003240				3270+	DS	0FD	
00003240		00003240		3271+	USING	*, R5	base for test data and test routine
00003240	0000325C			3272+T96	DC	A(X96)	address of test routine
00003244	0060			3273+	DC	H' 96'	test number
00003246	00			3274+	DC	XL1' 00'	
00003247	9F			3275+	DC	HL1' 159'	i3
00003248	0B			3276+	DC	HL1' 11'	m4
00003249	00			3277+	DC	HL1' 0'	cc
0000324A	07			3278+	DC	HL1' 7'	cc failed mask
0000324B	E5C3E5C4 C7404040			3279+	DC	CL8' VCVDG'	instruction name
00003254	00000010			3280+	DC	A(16)	result length
00003258	00003280			3281+REA96	DC	A(RE96)	result address
				3282+*			INSTRUCTION UNDER TEST ROUTINE
0000325C				3283+X96	DS	0F	
0000325C	E710 8F48 0006		00001148	3284+	VL	V1, V1FUDGE	pollute V1
00003262	E320 5050 0004		00003290	3285+	LG	R2, RE96+16	get R2 source
00003268	E612 00B9 F05A			3286+	VCVDG	V1, R2, 159, 11	test instruction
0000326E	E710 8F10 000E		00001110	3287+	VST	V1, V10UTPUT	save
00003274	B98D 0020			3288+	EPSW	R2, R0	exptract psw
00003278	5020 8EE8		000010E8	3289+	ST	R2, CCPSW	to save CC
0000327C	07FB			3290+	BR	R11	return
00003280				3291+RE96	DC	0F	
00003280				3292+	DROP	R5	
00003280	00000000 00018446			3293	DC	XL16' 00000000000018446744073709551615F'	V1 source
00003288	74407370 9551615F						
00003290	FFFFFFFF FFFFFFFF			3294	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result
				3295			
				3296 * VCVDG		m4= 11 (LB=1, P1=1 , CS=1)	
				3297 *		i3= 137 (IOM=1, RDC= 9)	
				3298			
				3299	VRR_K	VCVDG, 137, 11, 0	
00003298				3300+	DS	0FD	
00003298		00003298		3301+	USING	*, R5	base for test data and test routine
00003298	000032B4			3302+T97	DC	A(X97)	address of test routine
0000329C	0061			3303+	DC	H' 97'	test number
0000329E	00			3304+	DC	XL1' 00'	
0000329F	89			3305+	DC	HL1' 137'	i3
000032A0	0B			3306+	DC	HL1' 11'	m4
000032A1	00			3307+	DC	HL1' 0'	cc
000032A2	07			3308+	DC	HL1' 7'	cc failed mask
000032A3	E5C3E5C4 C7404040			3309+	DC	CL8' VCVDG'	instruction name
000032AC	00000010			3310+	DC	A(16)	result length
000032B0	000032D8			3311+REA97	DC	A(RE97)	result address
				3312+*			INSTRUCTION UNDER TEST ROUTINE
000032B4				3313+X97	DS	0F	
000032B4	E710 8F48 0006		00001148	3314+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000032BA	E320 5050 0004		000032E8	3315+	LG	R2, RE97+16	get R2 source
000032C0	E612 00B8 905A			3316+	VCVDG	V1, R2, 137, 11	test instruction
000032C6	E710 8F10 000E		00001110	3317+	VST	V1, V10UTPUT	save
000032CC	B98D 0020			3318+	EPSW	R2, R0	exptract psw
000032D0	5020 8EE8		000010E8	3319+	ST	R2, CCPSW	to save CC
000032D4	07FB			3320+	BR	R11	return
000032D8				3321+RE97	DC	0F	
000032D8				3322+	DROP	R5	
000032D8	00000000 00000000			3323	DC	XL16' 00000000000000000000000000000000F'	V1 result
000032E0	00000000 0000000F						
000032E8	00000000 00000000			3324	DC	FD' 0'	R2 source
				3325			
				3326	VRR_K	VCVDG, 137, 11, 0	
000032F0				3327+	DS	0FD	
000032F0		000032F0		3328+	USING	*, R5	base for test data and test routine
000032F0	0000330C			3329+T98	DC	A(X98)	address of test routine
000032F4	0062			3330+	DC	H' 98'	test number
000032F6	00			3331+	DC	XL1' 00'	
000032F7	89			3332+	DC	HL1' 137'	i3
000032F8	0B			3333+	DC	HL1' 11'	m4
000032F9	00			3334+	DC	HL1' 0'	cc
000032FA	07			3335+	DC	HL1' 7'	cc failed mask
000032FB	E5C3E5C4 C7404040			3336+	DC	CL8' VCVDG'	instruction name
00003304	00000010			3337+	DC	A(16)	result length
00003308	00003330			3338+REA98	DC	A(RE98)	result address
				3339+*			INSTRUCTION UNDER TEST ROUTINE
0000330C				3340+X98	DS	0F	
0000330C	E710 8F48 0006		00001148	3341+	VL	V1, V1FUDGE	pollute V1
00003312	E320 5050 0004		00003340	3342+	LG	R2, RE98+16	get R2 source
00003318	E612 00B8 905A			3343+	VCVDG	V1, R2, 137, 11	test instruction
0000331E	E710 8F10 000E		00001110	3344+	VST	V1, V10UTPUT	save
00003324	B98D 0020			3345+	EPSW	R2, R0	exptract psw
00003328	5020 8EE8		000010E8	3346+	ST	R2, CCPSW	to save CC
0000332C	07FB			3347+	BR	R11	return
00003330				3348+RE98	DC	0F	
00003330				3349+	DROP	R5	
00003330	00000000 00000000			3350	DC	XL16' 000000000000000000000000000000001F'	V1 result
00003338	00000000 0000001F						
00003340	00000000 00000001			3351	DC	FD' 1'	R2 source
				3352			
				3353	VRR_K	VCVDG, 137, 11, 3	UINT_MAX
00003348				3354+	DS	0FD	
00003348		00003348		3355+	USING	*, R5	base for test data and test routine
00003348	00003364			3356+T99	DC	A(X99)	address of test routine
0000334C	0063			3357+	DC	H' 99'	test number
0000334E	00			3358+	DC	XL1' 00'	
0000334F	89			3359+	DC	HL1' 137'	i3
00003350	0B			3360+	DC	HL1' 11'	m4
00003351	03			3361+	DC	HL1' 3'	cc
00003352	0E			3362+	DC	HL1' 14'	cc failed mask
00003353	E5C3E5C4 C7404040			3363+	DC	CL8' VCVDG'	instruction name
0000335C	00000010			3364+	DC	A(16)	result length
00003360	00003388			3365+REA99	DC	A(RE99)	result address
				3366+*			INSTRUCTION UNDER TEST ROUTINE
00003364				3367+X99	DS	0F	
00003364	E710 8F48 0006		00001148	3368+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000336A	E320 5050 0004		00003398	3369+	LG	R2, RE99+16	get R2 source
00003370	E612 00B8 905A			3370+	VCVDG	V1, R2, 137, 11	test instruction
00003376	E710 8F10 000E		00001110	3371+	VST	V1, V10UTPUT	save
0000337C	B98D 0020			3372+	EPSW	R2, R0	exptract psw
00003380	5020 8EE8		000010E8	3373+	ST	R2, CCPSW	to save CC
00003384	07FB			3374+	BR	R11	return
00003388				3375+RE99	DC	0F	
00003388				3376+	DROP	R5	
00003388	00000000 00000000			3377	DC	XL16' 000000000000000000000000709551615F'	V1 source
00003390	00000070 9551615F						
00003398	FFFFFFFF FFFFFFFF			3378	DC	FD' - 1'	R2 source
				3379			
				3380	VRR_K	VCVDG, 137, 11, 3	INT_MAX
000033A0				3381+	DS	0FD	
000033A0		000033A0		3382+	USING	*, R5	base for test data and test routine
000033A0	000033BC			3383+T100	DC	A(X100)	address of test routine
000033A4	0064			3384+	DC	H' 100'	test number
000033A6	00			3385+	DC	XL1' 00'	
000033A7	89			3386+	DC	HL1' 137'	i3
000033A8	0B			3387+	DC	HL1' 11'	m4
000033A9	03			3388+	DC	HL1' 3'	cc
000033AA	0E			3389+	DC	HL1' 14'	cc failed mask
000033AB	E5C3E5C4 C7404040			3390+	DC	CL8' VCVDG'	instruction name
000033B4	00000010			3391+	DC	A(16)	result length
000033B8	000033E0			3392+REA100	DC	A(RE100)	result address
				3393+*			INSTRUCTION UNDER TEST ROUTINE
000033BC				3394+X100	DS	0F	
000033BC	E710 8F48 0006		00001148	3395+	VL	V1, V1FUDGE	pollute V1
000033C2	E320 5050 0004		000033F0	3396+	LG	R2, RE100+16	get R2 source
000033C8	E612 00B8 905A			3397+	VCVDG	V1, R2, 137, 11	test instruction
000033CE	E710 8F10 000E		00001110	3398+	VST	V1, V10UTPUT	save
000033D4	B98D 0020			3399+	EPSW	R2, R0	exptract psw
000033D8	5020 8EE8		000010E8	3400+	ST	R2, CCPSW	to save CC
000033DC	07FB			3401+	BR	R11	return
000033E0				3402+RE100	DC	0F	
000033E0				3403+	DROP	R5	
000033E0	00000000 00000000			3404	DC	XL16' 000000000000000000000000147483647F'	V1 result
000033E8	00000014 7483647F						
000033F0	00000000 7FFFFFFF			3405	DC	FD' 2147483647'	R2 source
				3406			
				3407	VRR_K	VCVDG, 137, 11, 3	INT_MIN
000033F8				3408+	DS	0FD	
000033F8		000033F8		3409+	USING	*, R5	base for test data and test routine
000033F8	00003414			3410+T101	DC	A(X101)	address of test routine
000033FC	0065			3411+	DC	H' 101'	test number
000033FE	00			3412+	DC	XL1' 00'	
000033FF	89			3413+	DC	HL1' 137'	i3
00003400	0B			3414+	DC	HL1' 11'	m4
00003401	03			3415+	DC	HL1' 3'	cc
00003402	0E			3416+	DC	HL1' 14'	cc failed mask
00003403	E5C3E5C4 C7404040			3417+	DC	CL8' VCVDG'	instruction name
0000340C	00000010			3418+	DC	A(16)	result length
00003410	00003438			3419+REA101	DC	A(RE101)	result address
				3420+*			INSTRUCTION UNDER TEST ROUTINE
00003414				3421+X101	DS	0F	
00003414	E710 8F48 0006		00001148	3422+	VL	V1, V1FUDGE	pollute V1

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000341A	E320 5050 0004		00003448	3423+	LG	R2, RE101+16	get R2 source
00003420	E612 00B8 905A			3424+	VCVDG	V1, R2, 137, 11	test instruction
00003426	E710 8F10 000E		00001110	3425+	VST	V1, V10UTPUT	save
0000342C	B98D 0020			3426+	EPSW	R2, R0	exptract psw
00003430	5020 8EE8		000010E8	3427+	ST	R2, CCPSW	to save CC
00003434	07FB			3428+	BR	R11	return
00003438				3429+RE101	DC	0F	
00003438				3430+	DROP	R5	
00003438	00000000 00000000			3431	DC	XL16' 000000000000000000000000562067968F'	V1 result
00003440	00000056 2067968F						
00003448	FFFFFFFF 80000000			3432	DC	XL8' FFFFFFFF80000000'	R2 source
				3433 *	DC	FD' - 2147483648'	R2 sourc
				3434			
				3435	VRR_K	VCVDG, 137, 11, 3	LONG_MAX
00003450				3436+	DS	0FD	
00003450		00003450		3437+	USING	*, R5	base for test data and test routine
00003450	0000346C			3438+T102	DC	A(X102)	address of test routine
00003454	0066			3439+	DC	H' 102'	test number
00003456	00			3440+	DC	XL1' 00'	
00003457	89			3441+	DC	HL1' 137'	i3
00003458	0B			3442+	DC	HL1' 11'	m4
00003459	03			3443+	DC	HL1' 3'	cc
0000345A	0E			3444+	DC	HL1' 14'	cc failed mask
0000345B	E5C3E5C4 C7404040			3445+	DC	CL8' VCVDG'	instruction name
00003464	00000010			3446+	DC	A(16)	result length
00003468	00003490			3447+REA102	DC	A(RE102)	result address
				3448+*			INSTRUCTION UNDER TEST ROUTINE
0000346C				3449+X102	DS	0F	
0000346C	E710 8F48 0006		00001148	3450+	VL	V1, V1FUDGE	pollute V1
00003472	E320 5050 0004		000034A0	3451+	LG	R2, RE102+16	get R2 source
00003478	E612 00B8 905A			3452+	VCVDG	V1, R2, 137, 11	test instruction
0000347E	E710 8F10 000E		00001110	3453+	VST	V1, V10UTPUT	save
00003484	B98D 0020			3454+	EPSW	R2, R0	exptract psw
00003488	5020 8EE8		000010E8	3455+	ST	R2, CCPSW	to save CC
0000348C	07FB			3456+	BR	R11	return
00003490				3457+RE102	DC	0F	
00003490				3458+	DROP	R5	
00003490	00000000 00000000			3459	DC	XL16' 000000000000000000000000854775807F'	V1 source
00003498	00000085 4775807F						
000034A0	7FFFFFFFF FFFFFFFF			3460	DC	XL08' 7FFFFFFFFFFFFFFFFF'	R1 result
				3461			
				3462	VRR_K	VCVDG, 137, 11, 3	LONG_MIN
000034A8				3463+	DS	0FD	
000034A8		000034A8		3464+	USING	*, R5	base for test data and test routine
000034A8	000034C4			3465+T103	DC	A(X103)	address of test routine
000034AC	0067			3466+	DC	H' 103'	test number
000034AE	00			3467+	DC	XL1' 00'	
000034AF	89			3468+	DC	HL1' 137'	i3
000034B0	0B			3469+	DC	HL1' 11'	m4
000034B1	03			3470+	DC	HL1' 3'	cc
000034B2	0E			3471+	DC	HL1' 14'	cc failed mask
000034B3	E5C3E5C4 C7404040			3472+	DC	CL8' VCVDG'	instruction name
000034BC	00000010			3473+	DC	A(16)	result length
000034C0	000034E8			3474+REA103	DC	A(RE103)	result address
				3475+*			INSTRUCTION UNDER TEST ROUTINE
000034C4				3476+X103	DS	0F	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
000034C4	E710 8F48 0006		00001148	3477+	VL	V1, V1FUDGE	pollute V1	
000034CA	E320 5050 0004		000034F8	3478+	LG	R2, RE103+16	get R2 source	
000034D0	E612 00B8 905A			3479+	VCVDG	V1, R2, 137, 11	test instruction	
000034D6	E710 8F10 000E		00001110	3480+	VST	V1, V10UTPUT	save	
000034DC	B98D 0020			3481+	EPSW	R2, R0	exptract psw	
000034E0	5020 8EE8		000010E8	3482+	ST	R2, CCPSW	to save CC	
000034E4	07FB			3483+	BR	R11	return	
000034E8				3484+RE103	DC	0F		
000034E8				3485+	DROP	R5		
000034E8	00000000 00000000			3486	DC	XL16' 000000000000000000000000854775808F'	V1 source	
000034F0	00000085 4775808F							
000034F8	80000000 00000000			3487	DC	XL08' 800000000000000000'	R1 result	
				3488				
				3489	VRR_K	VCVDG, 137, 11, 3	ULONG_MAX	
00003500				3490+	DS	0FD		
00003500		00003500		3491+	USING	*, R5	base for test data and test routine	
00003500	0000351C			3492+T104	DC	A(X104)	address of test routine	
00003504	0068			3493+	DC	H' 104'	test number	
00003506	00			3494+	DC	XL1' 00'		
00003507	89			3495+	DC	HL1' 137'	i3	
00003508	0B			3496+	DC	HL1' 11'	m4	
00003509	03			3497+	DC	HL1' 3'	cc	
0000350A	0E			3498+	DC	HL1' 14'	cc failed mask	
0000350B	E5C3E5C4 C7404040			3499+	DC	CL8' VCVDG'	instruction name	
00003514	00000010			3500+	DC	A(16)	result length	
00003518	00003540			3501+REA104	DC	A(RE104)	result address	
				3502+*			INSTRUCTION UNDER TEST ROUTINE	
0000351C				3503+X104	DS	0F		
0000351C	E710 8F48 0006		00001148	3504+	VL	V1, V1FUDGE	pollute V1	
00003522	E320 5050 0004		00003550	3505+	LG	R2, RE104+16	get R2 source	
00003528	E612 00B8 905A			3506+	VCVDG	V1, R2, 137, 11	test instruction	
0000352E	E710 8F10 000E		00001110	3507+	VST	V1, V10UTPUT	save	
00003534	B98D 0020			3508+	EPSW	R2, R0	exptract psw	
00003538	5020 8EE8		000010E8	3509+	ST	R2, CCPSW	to save CC	
0000353C	07FB			3510+	BR	R11	return	
00003540				3511+RE104	DC	0F		
00003540				3512+	DROP	R5		
00003540	00000000 00000000			3513	DC	XL16' 000000000000000000000000709551615F'	V1 source	
00003548	00000070 9551615F							
00003550	FFFFFFFF FFFFFFFF			3514	DC	XL08' FFFFFFFFFFFFFFFFFF'	R1 result	
				3515				
00003558	00000000			3516	DC	F' 0'	END OF TABLE	
0000355C	00000000			3517	DC	F' 0'		
				3518 *				
				3519 *	table of pointers to individual load test			
				3520 *				
00003560				3521 E6TESTS	DS	0F		
				3522	PTTABLE			
00003560				3523+TTABLE	DS	0F		
00003560	00001198			3524+	DC	A(T1)	address of test	
00003564	000011F0			3525+	DC	A(T2)	address of test	
00003568	00001248			3526+	DC	A(T3)	address of test	
0000356C	000012A0			3527+	DC	A(T4)	address of test	
00003570	000012F8			3528+	DC	A(T5)	address of test	
00003574	00001350			3529+	DC	A(T6)	address of test	
00003578	000013A8			3530+	DC	A(T7)	address of test	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000357C	00001400			3531+	DC	A(T8)	address of test
00003580	00001458			3532+	DC	A(T9)	address of test
00003584	000014B0			3533+	DC	A(T10)	address of test
00003588	00001508			3534+	DC	A(T11)	address of test
0000358C	00001560			3535+	DC	A(T12)	address of test
00003590	000015B8			3536+	DC	A(T13)	address of test
00003594	00001610			3537+	DC	A(T14)	address of test
00003598	00001668			3538+	DC	A(T15)	address of test
0000359C	000016C0			3539+	DC	A(T16)	address of test
000035A0	00001718			3540+	DC	A(T17)	address of test
000035A4	00001770			3541+	DC	A(T18)	address of test
000035A8	000017C8			3542+	DC	A(T19)	address of test
000035AC	00001820			3543+	DC	A(T20)	address of test
000035B0	00001878			3544+	DC	A(T21)	address of test
000035B4	000018D0			3545+	DC	A(T22)	address of test
000035B8	00001928			3546+	DC	A(T23)	address of test
000035BC	00001980			3547+	DC	A(T24)	address of test
000035C0	000019D8			3548+	DC	A(T25)	address of test
000035C4	00001A30			3549+	DC	A(T26)	address of test
000035C8	00001A88			3550+	DC	A(T27)	address of test
000035CC	00001AE0			3551+	DC	A(T28)	address of test
000035D0	00001B38			3552+	DC	A(T29)	address of test
000035D4	00001B90			3553+	DC	A(T30)	address of test
000035D8	00001BE8			3554+	DC	A(T31)	address of test
000035DC	00001C40			3555+	DC	A(T32)	address of test
000035E0	00001C98			3556+	DC	A(T33)	address of test
000035E4	00001CF0			3557+	DC	A(T34)	address of test
000035E8	00001D48			3558+	DC	A(T35)	address of test
000035EC	00001DA0			3559+	DC	A(T36)	address of test
000035F0	00001DF8			3560+	DC	A(T37)	address of test
000035F4	00001E50			3561+	DC	A(T38)	address of test
000035F8	00001EA8			3562+	DC	A(T39)	address of test
000035FC	00001F00			3563+	DC	A(T40)	address of test
00003600	00001F58			3564+	DC	A(T41)	address of test
00003604	00001FB0			3565+	DC	A(T42)	address of test
00003608	00002008			3566+	DC	A(T43)	address of test
0000360C	00002060			3567+	DC	A(T44)	address of test
00003610	000020B8			3568+	DC	A(T45)	address of test
00003614	00002110			3569+	DC	A(T46)	address of test
00003618	00002168			3570+	DC	A(T47)	address of test
0000361C	000021C0			3571+	DC	A(T48)	address of test
00003620	00002218			3572+	DC	A(T49)	address of test
00003624	00002270			3573+	DC	A(T50)	address of test
00003628	000022C8			3574+	DC	A(T51)	address of test
0000362C	00002320			3575+	DC	A(T52)	address of test
00003630	00002378			3576+	DC	A(T53)	address of test
00003634	000023D0			3577+	DC	A(T54)	address of test
00003638	00002428			3578+	DC	A(T55)	address of test
0000363C	00002480			3579+	DC	A(T56)	address of test
00003640	000024D8			3580+	DC	A(T57)	address of test
00003644	00002530			3581+	DC	A(T58)	address of test
00003648	00002588			3582+	DC	A(T59)	address of test
0000364C	000025E0			3583+	DC	A(T60)	address of test
00003650	00002638			3584+	DC	A(T61)	address of test
00003654	00002690			3585+	DC	A(T62)	address of test
00003658	000026E8			3586+	DC	A(T63)	address of test

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000365C	00002740			3587+	DC	A(T64)	address of test
00003660	00002798			3588+	DC	A(T65)	address of test
00003664	000027F0			3589+	DC	A(T66)	address of test
00003668	00002848			3590+	DC	A(T67)	address of test
0000366C	000028A0			3591+	DC	A(T68)	address of test
00003670	000028F8			3592+	DC	A(T69)	address of test
00003674	00002950			3593+	DC	A(T70)	address of test
00003678	000029A8			3594+	DC	A(T71)	address of test
0000367C	00002A00			3595+	DC	A(T72)	address of test
00003680	00002A58			3596+	DC	A(T73)	address of test
00003684	00002AB0			3597+	DC	A(T74)	address of test
00003688	00002B08			3598+	DC	A(T75)	address of test
0000368C	00002B60			3599+	DC	A(T76)	address of test
00003690	00002BB8			3600+	DC	A(T77)	address of test
00003694	00002C10			3601+	DC	A(T78)	address of test
00003698	00002C68			3602+	DC	A(T79)	address of test
0000369C	00002CC0			3603+	DC	A(T80)	address of test
000036A0	00002D18			3604+	DC	A(T81)	address of test
000036A4	00002D70			3605+	DC	A(T82)	address of test
000036A8	00002DC8			3606+	DC	A(T83)	address of test
000036AC	00002E20			3607+	DC	A(T84)	address of test
000036B0	00002E78			3608+	DC	A(T85)	address of test
000036B4	00002ED0			3609+	DC	A(T86)	address of test
000036B8	00002F28			3610+	DC	A(T87)	address of test
000036BC	00002F80			3611+	DC	A(T88)	address of test
000036C0	00002FD8			3612+	DC	A(T89)	address of test
000036C4	00003030			3613+	DC	A(T90)	address of test
000036C8	00003088			3614+	DC	A(T91)	address of test
000036CC	000030E0			3615+	DC	A(T92)	address of test
000036D0	00003138			3616+	DC	A(T93)	address of test
000036D4	00003190			3617+	DC	A(T94)	address of test
000036D8	000031E8			3618+	DC	A(T95)	address of test
000036DC	00003240			3619+	DC	A(T96)	address of test
000036E0	00003298			3620+	DC	A(T97)	address of test
000036E4	000032F0			3621+	DC	A(T98)	address of test
000036E8	00003348			3622+	DC	A(T99)	address of test
000036EC	000033A0			3623+	DC	A(T100)	address of test
000036F0	000033F8			3624+	DC	A(T101)	address of test
000036F4	00003450			3625+	DC	A(T102)	address of test
000036F8	000034A8			3626+	DC	A(T103)	address of test
000036FC	00003500			3627+	DC	A(T104)	address of test
				3628+*			
00003700	00000000			3629+	DC	A(0)	END OF TABLE
00003704	00000000			3630+	DC	A(0)	
				3631			
00003708	00000000			3632	DC	F' 0'	END OF TABLE
0000370C	00000000			3633	DC	F' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				3635 *****	
				3636 * Register equates	
				3637 *****	
		00000000	00000001	3639 R0	EQU 0
		00000001	00000001	3640 R1	EQU 1
		00000002	00000001	3641 R2	EQU 2
		00000003	00000001	3642 R3	EQU 3
		00000004	00000001	3643 R4	EQU 4
		00000005	00000001	3644 R5	EQU 5
		00000006	00000001	3645 R6	EQU 6
		00000007	00000001	3646 R7	EQU 7
		00000008	00000001	3647 R8	EQU 8
		00000009	00000001	3648 R9	EQU 9
		0000000A	00000001	3649 R10	EQU 10
		0000000B	00000001	3650 R11	EQU 11
		0000000C	00000001	3651 R12	EQU 12
		0000000D	00000001	3652 R13	EQU 13
		0000000E	00000001	3653 R14	EQU 14
		0000000F	00000001	3654 R15	EQU 15
				3656 *****	
				3657 * Register equates	
				3658 *****	
		00000000	00000001	3660 V0	EQU 0
		00000001	00000001	3661 V1	EQU 1
		00000002	00000001	3662 V2	EQU 2
		00000003	00000001	3663 V3	EQU 3
		00000004	00000001	3664 V4	EQU 4
		00000005	00000001	3665 V5	EQU 5
		00000006	00000001	3666 V6	EQU 6
		00000007	00000001	3667 V7	EQU 7
		00000008	00000001	3668 V8	EQU 8
		00000009	00000001	3669 V9	EQU 9
		0000000A	00000001	3670 V10	EQU 10
		0000000B	00000001	3671 V11	EQU 11
		0000000C	00000001	3672 V12	EQU 12
		0000000D	00000001	3673 V13	EQU 13
		0000000E	00000001	3674 V14	EQU 14
		0000000F	00000001	3675 V15	EQU 15
		00000010	00000001	3676 V16	EQU 16
		00000011	00000001	3677 V17	EQU 17
		00000012	00000001	3678 V18	EQU 18
		00000013	00000001	3679 V19	EQU 19
		00000014	00000001	3680 V20	EQU 20
		00000015	00000001	3681 V21	EQU 21

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES													
PRTNAME	C	00001033	8	452	291													
PRTNUM	C	00001018	3	450	289													
R0	U	00000000	1	3639	111	162	165	185	187	188	189	194	211	273	307	315	316	
					342	344	360	363	365	367	369	384	661	688	715	742	769	
					799	826	853	880	907	938	965	992	1019	1046	1076	1103	1130	
					1157	1184	1215	1242	1269	1296	1323	1353	1380	1407	1434	1461	1492	
					1519	1546	1573	1600	1630	1657	1684	1711	1738	1780	1807	1834	1861	
					1888	1915	1942	1969	1999	2026	2053	2080	2107	2134	2161	2188	2219	
					2246	2273	2300	2327	2354	2381	2408	2438	2465	2492	2519	2546	2573	
					2600	2627	2658	2685	2712	2739	2766	2794	2821	2848	2878	2905	2932	
					2959	2986	3013	3040	3067	3098	3125	3152	3179	3206	3234	3261	3288	
					3318	3345	3372	3399	3426	3454	3481	3508						
R1	U	00000001	1	3640	195	218	219	220	223	224	237	238	239	244	245	246	247	
					274	308	325	326	374	388								
R10	U	0000000A	1	3649	150	159	160											
R11	U	0000000B	1	3650	215	216	663	690	717	744	771	801	828	855	882	909	940	
					967	994	1021	1048	1078	1105	1132	1159	1186	1217	1244	1271	1298	
					1325	1355	1382	1409	1436	1463	1494	1521	1548	1575	1602	1632	1659	
					1686	1713	1740	1782	1809	1836	1863	1890	1917	1944	1971	2001	2028	
					2055	2082	2109	2136	2163	2190	2221	2248	2275	2302	2329	2356	2383	
					2410	2440	2467	2494	2521	2548	2575	2602	2629	2660	2687	2714	2741	
					2768	2796	2823	2850	2880	2907	2934	2961	2988	3015	3042	3069	3100	
					3127	3154	3181	3208	3236	3263	3290	3320	3347	3374	3401	3428	3456	
					3483	3510												
					204	207	227	318										
R12	U	0000000C	1	3651														
R13	U	0000000D	1	3652														
R14	U	0000000E	1	3653														
R15	U	0000000F	1	3654	275	309	337	347	348									
R1FUDGE	X	000010F8	8	497														
R1OUTPUT	F	00001130	8	501														
R2	U	00000002	1	3641	196	251	252	259	260	261	266	267	268	285	286	293	294	
					295	300	301	302	342	343	344	361	363	369	370	371	373	
					379	384	385	658	659	661	662	685	686	688	689	712	713	
					715	716	739	740	742	743	766	767	769	770	796	797	799	
					800	823	824	826	827	850	851	853	854	877	878	880	881	
					904	905	907	908	935	936	938	939	962	963	965	966	989	
					990	992	993	1016	1017	1019	1020	1043	1044	1046	1047	1073	1074	
					1076	1077	1100	1101	1103	1104	1127	1128	1130	1131	1154	1155	1157	
					1158	1181	1182	1184	1185	1212	1213	1215	1216	1239	1240	1242	1243	
					1266	1267	1269	1270	1293	1294	1296	1297	1320	1321	1323	1324	1350	
					1351	1353	1354	1377	1378	1380	1381	1404	1405	1407	1408	1431	1432	
					1434	1435	1458	1459	1461	1462	1489	1490	1492	1493	1516	1517	1519	
					1520	1543	1544	1546	1547	1570	1571	1573	1574	1597	1598	1600	1601	
					1627	1628	1630	1631	1654	1655	1657	1658	1681	1682	1684	1685	1708	
					1709	1711	1712	1735	1736	1738	1739	1777	1778	1780	1781	1804	1805	
					1807	1808	1831	1832	1834	1835	1858	1859	1861	1862	1885	1886	1888	
					1889	1912	1913	1915	1916	1939	1940	1942	1943	1966	1967	1969	1970	
					1996	1997	1999	2000	2023	2024	2026	2027	2050	2051	2053	2054	2077	
					2078	2080	2081	2104	2105	2107	2108	2131	2132	2134	2135	2158	2159	
					2161	2162	2185	2186	2188	2189	2216	2217	2219	2220	2243	2244	2246	
					2247	2270	2271	2273	2274	2297	2298	2300	2301	2324	2325	2327	2328	
					2351	2352	2354	2355	2378	2379	2381	2382	2405	2406	2408	2409	2435	
					2436	2438	2439	2462	2463	2465	2466	2489	2490	2492	2493	2516	2517	
					2519	2520	2543	2544	2546	2547	2570	2571	2573	2574	2597	2598	2600	
					2601	2624	2625	2627	2628	2655	2656	2658	2659	2682	2683	2685	2686	
					2709	2710	2712	2713	2736	2737	2739	2740	2763	2764	2766	2767	2791	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES													
						2792	2794	2795	2818	2819	2821	2822	2845	2846	2848	2849	2875	2876
						2878	2879	2902	2903	2905	2906	2929	2930	2932	2933	2956	2957	2959
						2960	2983	2984	2986	2987	3010	3011	3013	3014	3037	3038	3040	3041
						3064	3065	3067	3068	3095	3096	3098	3099	3122	3123	3125	3126	3149
						3150	3152	3153	3176	3177	3179	3180	3203	3204	3206	3207	3231	3232
						3234	3235	3258	3259	3261	3262	3285	3286	3288	3289	3315	3316	3318
						3319	3342	3343	3345	3346	3369	3370	3372	3373	3396	3397	3399	3400
						3423	3424	3426	3427	3451	3452	3454	3455	3478	3479	3481	3482	3505
						3506	3508	3509										
R3	U	00000003	1	3642														
R4	U	00000004	1	3643														
R5	U	00000005	1	3644	207	208	213	338	346	644	665	671	692	698	719	725	746	
					752	773	782	803	809	830	836	857	863	884	890	911	921	
					942	948	969	975	996	1002	1023	1029	1050	1059	1080	1086	1107	
					1113	1134	1140	1161	1167	1188	1198	1219	1225	1246	1252	1273	1279	
					1300	1306	1327	1336	1357	1363	1384	1390	1411	1417	1438	1444	1465	
					1475	1496	1502	1523	1529	1550	1556	1577	1583	1604	1613	1634	1640	
					1661	1667	1688	1694	1715	1721	1742	1763	1784	1790	1811	1817	1838	
					1844	1865	1871	1892	1898	1919	1925	1946	1952	1973	1982	2003	2009	
					2030	2036	2057	2063	2084	2090	2111	2117	2138	2144	2165	2171	2192	
					2202	2223	2229	2250	2256	2277	2283	2304	2310	2331	2337	2358	2364	
					2385	2391	2412	2421	2442	2448	2469	2475	2496	2502	2523	2529	2550	
					2556	2577	2583	2604	2610	2631	2641	2662	2668	2689	2695	2716	2722	
					2743	2749	2770	2777	2798	2804	2825	2831	2852	2861	2882	2888	2909	
					2915	2936	2942	2963	2969	2990	2996	3017	3023	3044	3050	3071	3081	
					3102	3108	3129	3135	3156	3162	3183	3189	3210	3217	3238	3244	3265	
					3271	3292	3301	3322	3328	3349	3355	3376	3382	3403	3409	3430	3437	
					3458	3464	3485	3491	3512									
R6	U	00000006	1	3645														
R7	U	00000007	1	3646														
R8	U	00000008	1	3647	148	152	153	154	156									
R9	U	00000009	1	3648	149	156	157	159										
RE1	F	000011D8	4	664	654	658												
RE10	F	000014F0	4	910	900	904												
RE100	F	000033E0	4	3402	3392	3396												
RE101	F	00003438	4	3429	3419	3423												
RE102	F	00003490	4	3457	3447	3451												
RE103	F	000034E8	4	3484	3474	3478												
RE104	F	00003540	4	3511	3501	3505												
RE11	F	00001548	4	941	931	935												
RE12	F	000015A0	4	968	958	962												
RE13	F	000015F8	4	995	985	989												
RE14	F	00001650	4	1022	1012	1016												
RE15	F	000016A8	4	1049	1039	1043												
RE16	F	00001700	4	1079	1069	1073												
RE17	F	00001758	4	1106	1096	1100												
RE18	F	000017B0	4	1133	1123	1127												
RE19	F	00001808	4	1160	1150	1154												
RE2	F	00001230	4	691	681	685												
RE20	F	00001860	4	1187	1177	1181												
RE21	F	000018B8	4	1218	1208	1212												
RE22	F	00001910	4	1245	1235	1239												
RE23	F	00001968	4	1272	1262	1266												
RE24	F	000019C0	4	1299	1289	1293												
RE25	F	00001A18	4	1326	1316	1320												
RE26	F	00001A70	4	1356	1346	1350												

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
RE27	F	00001AC8	4	1383	1373 1377
RE28	F	00001B20	4	1410	1400 1404
RE29	F	00001B78	4	1437	1427 1431
RE3	F	00001288	4	718	708 712
RE30	F	00001BD0	4	1464	1454 1458
RE31	F	00001C28	4	1495	1485 1489
RE32	F	00001C80	4	1522	1512 1516
RE33	F	00001CD8	4	1549	1539 1543
RE34	F	00001D30	4	1576	1566 1570
RE35	F	00001D88	4	1603	1593 1597
RE36	F	00001DE0	4	1633	1623 1627
RE37	F	00001E38	4	1660	1650 1654
RE38	F	00001E90	4	1687	1677 1681
RE39	F	00001EE8	4	1714	1704 1708
RE4	F	000012E0	4	745	735 739
RE40	F	00001F40	4	1741	1731 1735
RE41	F	00001F98	4	1783	1773 1777
RE42	F	00001FF0	4	1810	1800 1804
RE43	F	00002048	4	1837	1827 1831
RE44	F	000020A0	4	1864	1854 1858
RE45	F	000020F8	4	1891	1881 1885
RE46	F	00002150	4	1918	1908 1912
RE47	F	000021A8	4	1945	1935 1939
RE48	F	00002200	4	1972	1962 1966
RE49	F	00002258	4	2002	1992 1996
RE5	F	00001338	4	772	762 766
RE50	F	000022B0	4	2029	2019 2023
RE51	F	00002308	4	2056	2046 2050
RE52	F	00002360	4	2083	2073 2077
RE53	F	000023B8	4	2110	2100 2104
RE54	F	00002410	4	2137	2127 2131
RE55	F	00002468	4	2164	2154 2158
RE56	F	000024C0	4	2191	2181 2185
RE57	F	00002518	4	2222	2212 2216
RE58	F	00002570	4	2249	2239 2243
RE59	F	000025C8	4	2276	2266 2270
RE6	F	00001390	4	802	792 796
RE60	F	00002620	4	2303	2293 2297
RE61	F	00002678	4	2330	2320 2324
RE62	F	000026D0	4	2357	2347 2351
RE63	F	00002728	4	2384	2374 2378
RE64	F	00002780	4	2411	2401 2405
RE65	F	000027D8	4	2441	2431 2435
RE66	F	00002830	4	2468	2458 2462
RE67	F	00002888	4	2495	2485 2489
RE68	F	000028E0	4	2522	2512 2516
RE69	F	00002938	4	2549	2539 2543
RE7	F	000013E8	4	829	819 823
RE70	F	00002990	4	2576	2566 2570
RE71	F	000029E8	4	2603	2593 2597
RE72	F	00002A40	4	2630	2620 2624
RE73	F	00002A98	4	2661	2651 2655
RE74	F	00002AF0	4	2688	2678 2682
RE75	F	00002B48	4	2715	2705 2709
RE76	F	00002BA0	4	2742	2732 2736
RE77	F	00002BF8	4	2769	2759 2763

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES		
RE78	F	00002C50	4	2797	2787	2791	
RE79	F	00002CA8	4	2824	2814	2818	
RE8	F	00001440	4	856	846	850	
RE80	F	00002D00	4	2851	2841	2845	
RE81	F	00002D58	4	2881	2871	2875	
RE82	F	00002DB0	4	2908	2898	2902	
RE83	F	00002E08	4	2935	2925	2929	
RE84	F	00002E60	4	2962	2952	2956	
RE85	F	00002EB8	4	2989	2979	2983	
RE86	F	00002F10	4	3016	3006	3010	
RE87	F	00002F68	4	3043	3033	3037	
RE88	F	00002FC0	4	3070	3060	3064	
RE89	F	00003018	4	3101	3091	3095	
RE9	F	00001498	4	883	873	877	
RE90	F	00003070	4	3128	3118	3122	
RE91	F	000030C8	4	3155	3145	3149	
RE92	F	00003120	4	3182	3172	3176	
RE93	F	00003178	4	3209	3199	3203	
RE94	F	000031D0	4	3237	3227	3231	
RE95	F	00003228	4	3264	3254	3258	
RE96	F	00003280	4	3291	3281	3285	
RE97	F	000032D8	4	3321	3311	3315	
RE98	F	00003330	4	3348	3338	3342	
RE99	F	00003388	4	3375	3365	3369	
REA1	A	000011B0	4	654			
REA10	A	000014C8	4	900			
REA100	A	000033B8	4	3392			
REA101	A	00003410	4	3419			
REA102	A	00003468	4	3447			
REA103	A	000034C0	4	3474			
REA104	A	00003518	4	3501			
REA11	A	00001520	4	931			
REA12	A	00001578	4	958			
REA13	A	000015D0	4	985			
REA14	A	00001628	4	1012			
REA15	A	00001680	4	1039			
REA16	A	000016D8	4	1069			
REA17	A	00001730	4	1096			
REA18	A	00001788	4	1123			
REA19	A	000017E0	4	1150			
REA2	A	00001208	4	681			
REA20	A	00001838	4	1177			
REA21	A	00001890	4	1208			
REA22	A	000018E8	4	1235			
REA23	A	00001940	4	1262			
REA24	A	00001998	4	1289			
REA25	A	000019F0	4	1316			
REA26	A	00001A48	4	1346			
REA27	A	00001AA0	4	1373			
REA28	A	00001AF8	4	1400			
REA29	A	00001B50	4	1427			
REA3	A	00001260	4	708			
REA30	A	00001BA8	4	1454			
REA31	A	00001C00	4	1485			
REA32	A	00001C58	4	1512			
REA33	A	00001CB0	4	1539			

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA34	A	00001D08	4	1566	
REA35	A	00001D60	4	1593	
REA36	A	00001DB8	4	1623	
REA37	A	00001E10	4	1650	
REA38	A	00001E68	4	1677	
REA39	A	00001EC0	4	1704	
REA4	A	000012B8	4	735	
REA40	A	00001F18	4	1731	
REA41	A	00001F70	4	1773	
REA42	A	00001FC8	4	1800	
REA43	A	00002020	4	1827	
REA44	A	00002078	4	1854	
REA45	A	000020D0	4	1881	
REA46	A	00002128	4	1908	
REA47	A	00002180	4	1935	
REA48	A	000021D8	4	1962	
REA49	A	00002230	4	1992	
REA5	A	00001310	4	762	
REA50	A	00002288	4	2019	
REA51	A	000022E0	4	2046	
REA52	A	00002338	4	2073	
REA53	A	00002390	4	2100	
REA54	A	000023E8	4	2127	
REA55	A	00002440	4	2154	
REA56	A	00002498	4	2181	
REA57	A	000024F0	4	2212	
REA58	A	00002548	4	2239	
REA59	A	000025A0	4	2266	
REA6	A	00001368	4	792	
REA60	A	000025F8	4	2293	
REA61	A	00002650	4	2320	
REA62	A	000026A8	4	2347	
REA63	A	00002700	4	2374	
REA64	A	00002758	4	2401	
REA65	A	000027B0	4	2431	
REA66	A	00002808	4	2458	
REA67	A	00002860	4	2485	
REA68	A	000028B8	4	2512	
REA69	A	00002910	4	2539	
REA7	A	000013C0	4	819	
REA70	A	00002968	4	2566	
REA71	A	000029C0	4	2593	
REA72	A	00002A18	4	2620	
REA73	A	00002A70	4	2651	
REA74	A	00002AC8	4	2678	
REA75	A	00002B20	4	2705	
REA76	A	00002B78	4	2732	
REA77	A	00002BD0	4	2759	
REA78	A	00002C28	4	2787	
REA79	A	00002C80	4	2814	
REA8	A	00001418	4	846	
REA80	A	00002CD8	4	2841	
REA81	A	00002D30	4	2871	
REA82	A	00002D88	4	2898	
REA83	A	00002DE0	4	2925	
REA84	A	00002E38	4	2952	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
REA85	A	00002E90	4	2979		
REA86	A	00002EE8	4	3006		
REA87	A	00002F40	4	3033		
REA88	A	00002F98	4	3060		
REA89	A	00002FF0	4	3091		
REA9	A	00001470	4	873		
REA90	A	00003048	4	3118		
REA91	A	000030A0	4	3145		
REA92	A	000030F8	4	3172		
REA93	A	00003150	4	3199		
REA94	A	000031A8	4	3227		
REA95	A	00003200	4	3254		
REA96	A	00003258	4	3281		
REA97	A	000032B0	4	3311		
REA98	A	00003308	4	3338		
REA99	A	00003360	4	3365		
READDR	A	00000018	4	526	223	
REG2LOW	U	000000DD	1	430		
REG2PATT	U	AABBCCDD	1	429		
RELEN	A	00000014	4	525		
RPTDWSAV	D	00000458	8	353	342	344
RPTERROR	I	00000430	4	337	275	309
RPTSAVE	F	00000450	4	350	337	347
RPTSVR5	F	00000454	4	351	338	346
SKL0001	U	00000054	1	178	194	195
SKT0001	C	0000022A	26	175	178	
SVOLDPSW	U	00000140	0	113		
T1	A	00001198	4	645	3524	
T10	A	000014B0	4	891	3533	
T100	A	000033A0	4	3383	3623	
T101	A	000033F8	4	3410	3624	
T102	A	00003450	4	3438	3625	
T103	A	000034A8	4	3465	3626	
T104	A	00003500	4	3492	3627	
T11	A	00001508	4	922	3534	
T12	A	00001560	4	949	3535	
T13	A	000015B8	4	976	3536	
T14	A	00001610	4	1003	3537	
T15	A	00001668	4	1030	3538	
T16	A	000016C0	4	1060	3539	
T17	A	00001718	4	1087	3540	
T18	A	00001770	4	1114	3541	
T19	A	000017C8	4	1141	3542	
T2	A	000011F0	4	672	3525	
T20	A	00001820	4	1168	3543	
T21	A	00001878	4	1199	3544	
T22	A	000018D0	4	1226	3545	
T23	A	00001928	4	1253	3546	
T24	A	00001980	4	1280	3547	
T25	A	000019D8	4	1307	3548	
T26	A	00001A30	4	1337	3549	
T27	A	00001A88	4	1364	3550	
T28	A	00001AE0	4	1391	3551	
T29	A	00001B38	4	1418	3552	
T3	A	00001248	4	699	3526	
T30	A	00001B90	4	1445	3553	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
T31	A	00001BE8	4	1476	3554
T32	A	00001C40	4	1503	3555
T33	A	00001C98	4	1530	3556
T34	A	00001CF0	4	1557	3557
T35	A	00001D48	4	1584	3558
T36	A	00001DA0	4	1614	3559
T37	A	00001DF8	4	1641	3560
T38	A	00001E50	4	1668	3561
T39	A	00001EA8	4	1695	3562
T4	A	000012A0	4	726	3527
T40	A	00001F00	4	1722	3563
T41	A	00001F58	4	1764	3564
T42	A	00001FB0	4	1791	3565
T43	A	00002008	4	1818	3566
T44	A	00002060	4	1845	3567
T45	A	000020B8	4	1872	3568
T46	A	00002110	4	1899	3569
T47	A	00002168	4	1926	3570
T48	A	000021C0	4	1953	3571
T49	A	00002218	4	1983	3572
T5	A	000012F8	4	753	3528
T50	A	00002270	4	2010	3573
T51	A	000022C8	4	2037	3574
T52	A	00002320	4	2064	3575
T53	A	00002378	4	2091	3576
T54	A	000023D0	4	2118	3577
T55	A	00002428	4	2145	3578
T56	A	00002480	4	2172	3579
T57	A	000024D8	4	2203	3580
T58	A	00002530	4	2230	3581
T59	A	00002588	4	2257	3582
T6	A	00001350	4	783	3529
T60	A	000025E0	4	2284	3583
T61	A	00002638	4	2311	3584
T62	A	00002690	4	2338	3585
T63	A	000026E8	4	2365	3586
T64	A	00002740	4	2392	3587
T65	A	00002798	4	2422	3588
T66	A	000027F0	4	2449	3589
T67	A	00002848	4	2476	3590
T68	A	000028A0	4	2503	3591
T69	A	000028F8	4	2530	3592
T7	A	000013A8	4	810	3530
T70	A	00002950	4	2557	3593
T71	A	000029A8	4	2584	3594
T72	A	00002A00	4	2611	3595
T73	A	00002A58	4	2642	3596
T74	A	00002AB0	4	2669	3597
T75	A	00002B08	4	2696	3598
T76	A	00002B60	4	2723	3599
T77	A	00002BB8	4	2750	3600
T78	A	00002C10	4	2778	3601
T79	A	00002C68	4	2805	3602
T8	A	00001400	4	837	3531
T80	A	00002CC0	4	2832	3603
T81	A	00002D18	4	2862	3604

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
X16	F	000016DC	4	1071	1060
X17	F	00001734	4	1098	1087
X18	F	0000178C	4	1125	1114
X19	F	000017E4	4	1152	1141
X2	F	0000120C	4	683	672
X20	F	0000183C	4	1179	1168
X21	F	00001894	4	1210	1199
X22	F	000018EC	4	1237	1226
X23	F	00001944	4	1264	1253
X24	F	0000199C	4	1291	1280
X25	F	000019F4	4	1318	1307
X26	F	00001A4C	4	1348	1337
X27	F	00001AA4	4	1375	1364
X28	F	00001AFC	4	1402	1391
X29	F	00001B54	4	1429	1418
X3	F	00001264	4	710	699
X30	F	00001BAC	4	1456	1445
X31	F	00001C04	4	1487	1476
X32	F	00001C5C	4	1514	1503
X33	F	00001CB4	4	1541	1530
X34	F	00001D0C	4	1568	1557
X35	F	00001D64	4	1595	1584
X36	F	00001DBC	4	1625	1614
X37	F	00001E14	4	1652	1641
X38	F	00001E6C	4	1679	1668
X39	F	00001EC4	4	1706	1695
X4	F	000012BC	4	737	726
X40	F	00001F1C	4	1733	1722
X41	F	00001F74	4	1775	1764
X42	F	00001FCC	4	1802	1791
X43	F	00002024	4	1829	1818
X44	F	0000207C	4	1856	1845
X45	F	000020D4	4	1883	1872
X46	F	0000212C	4	1910	1899
X47	F	00002184	4	1937	1926
X48	F	000021DC	4	1964	1953
X49	F	00002234	4	1994	1983
X5	F	00001314	4	764	753
X50	F	0000228C	4	2021	2010
X51	F	000022E4	4	2048	2037
X52	F	0000233C	4	2075	2064
X53	F	00002394	4	2102	2091
X54	F	000023EC	4	2129	2118
X55	F	00002444	4	2156	2145
X56	F	0000249C	4	2183	2172
X57	F	000024F4	4	2214	2203
X58	F	0000254C	4	2241	2230
X59	F	000025A4	4	2268	2257
X6	F	0000136C	4	794	783
X60	F	000025FC	4	2295	2284
X61	F	00002654	4	2322	2311
X62	F	000026AC	4	2349	2338
X63	F	00002704	4	2376	2365
X64	F	0000275C	4	2403	2392
X65	F	000027B4	4	2433	2422
X66	F	0000280C	4	2460	2449

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	14096	0000- 370F	0000- 370F
Regi on		14096	0000- 370F	0000- 370F
CSECT	ZVE6TST	14096	0000- 370F	0000- 370F

STMT

FILE NAME

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1 /home/tn529/sharedvfp/tests/zvector-e6-13-converttodecimal.asm
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**** NO ERRORS FOUND ****